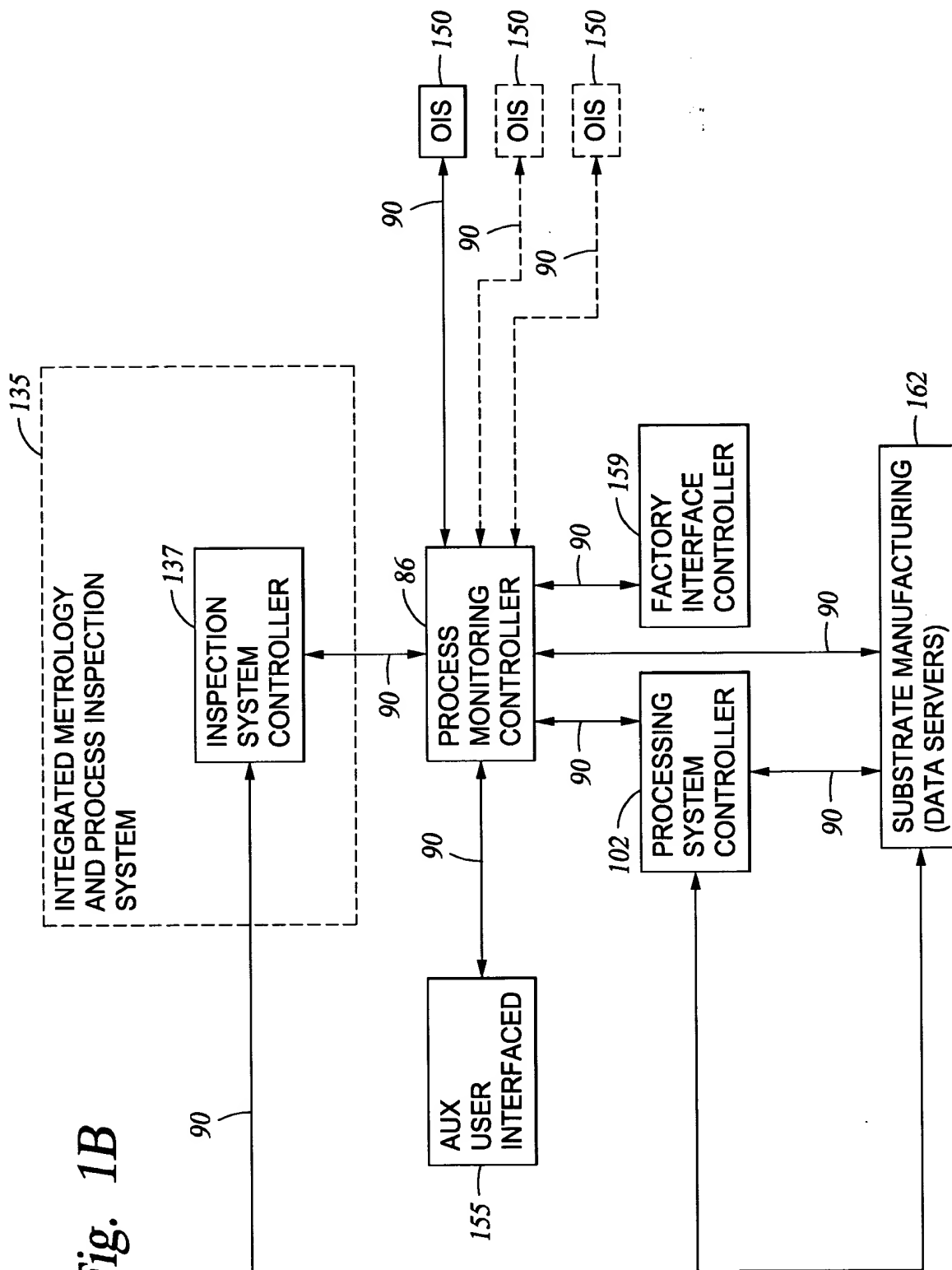


Fig. 1A

Fig. 1B



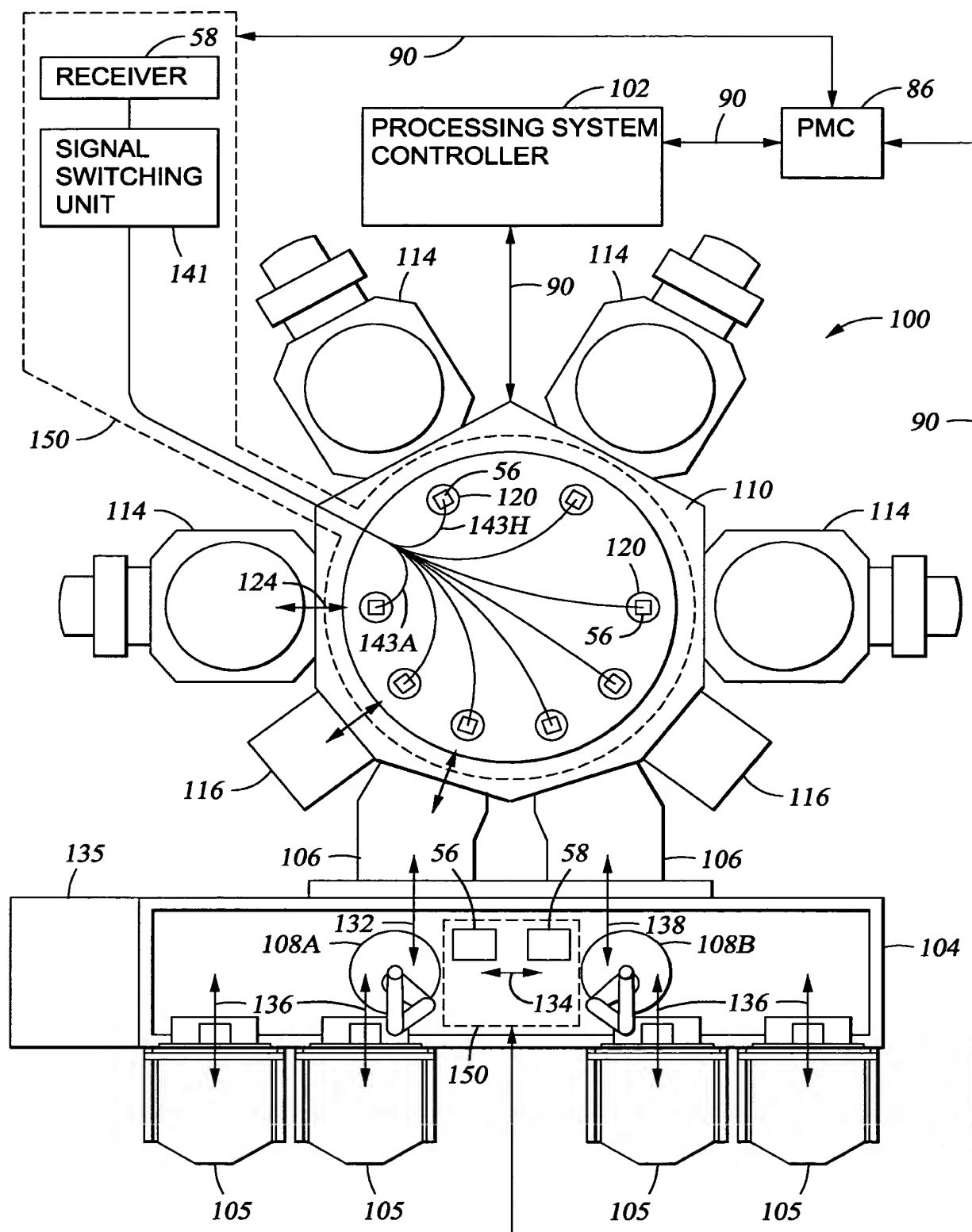


Fig. 1C

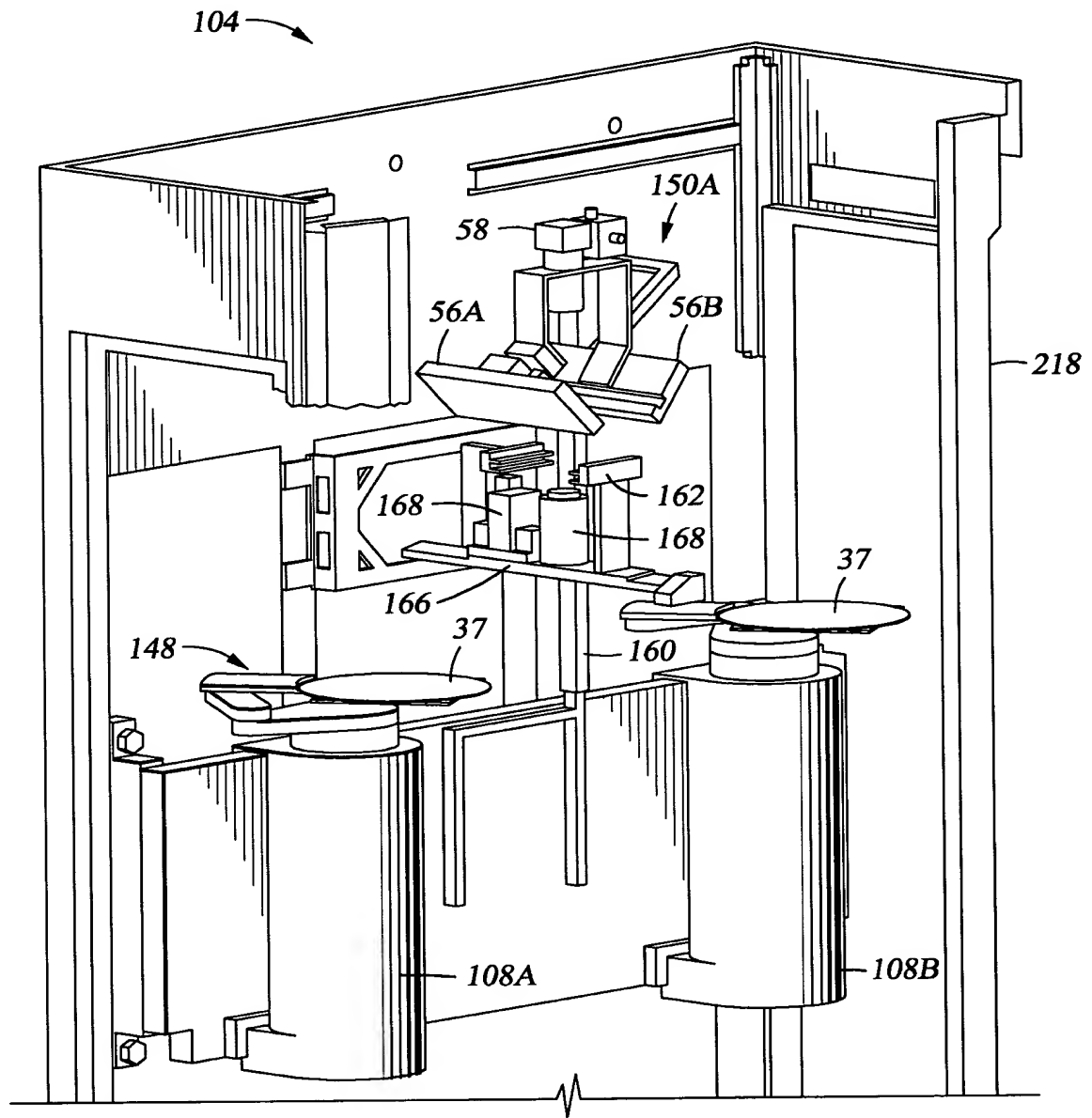


Fig. 2

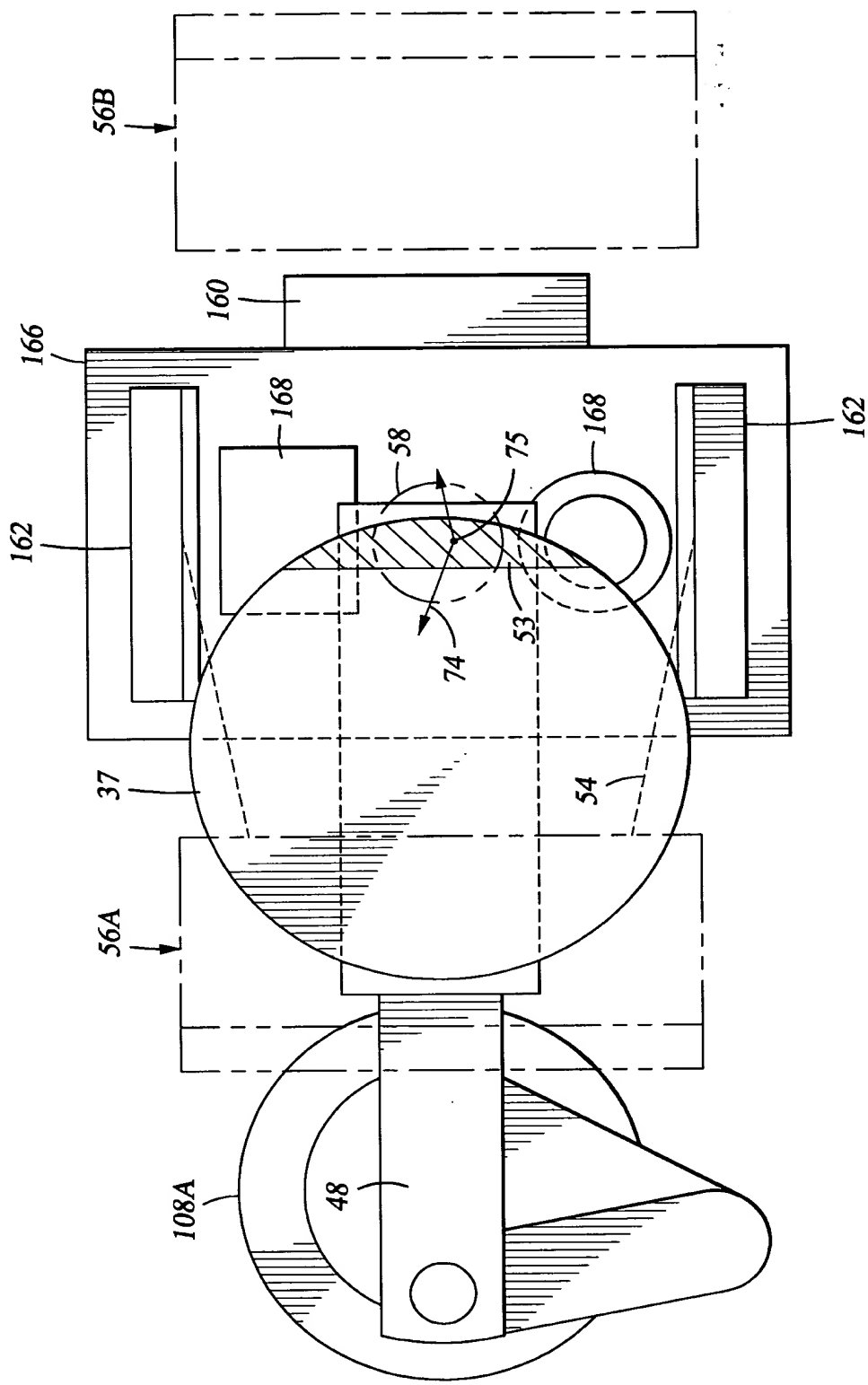


Fig. 3A

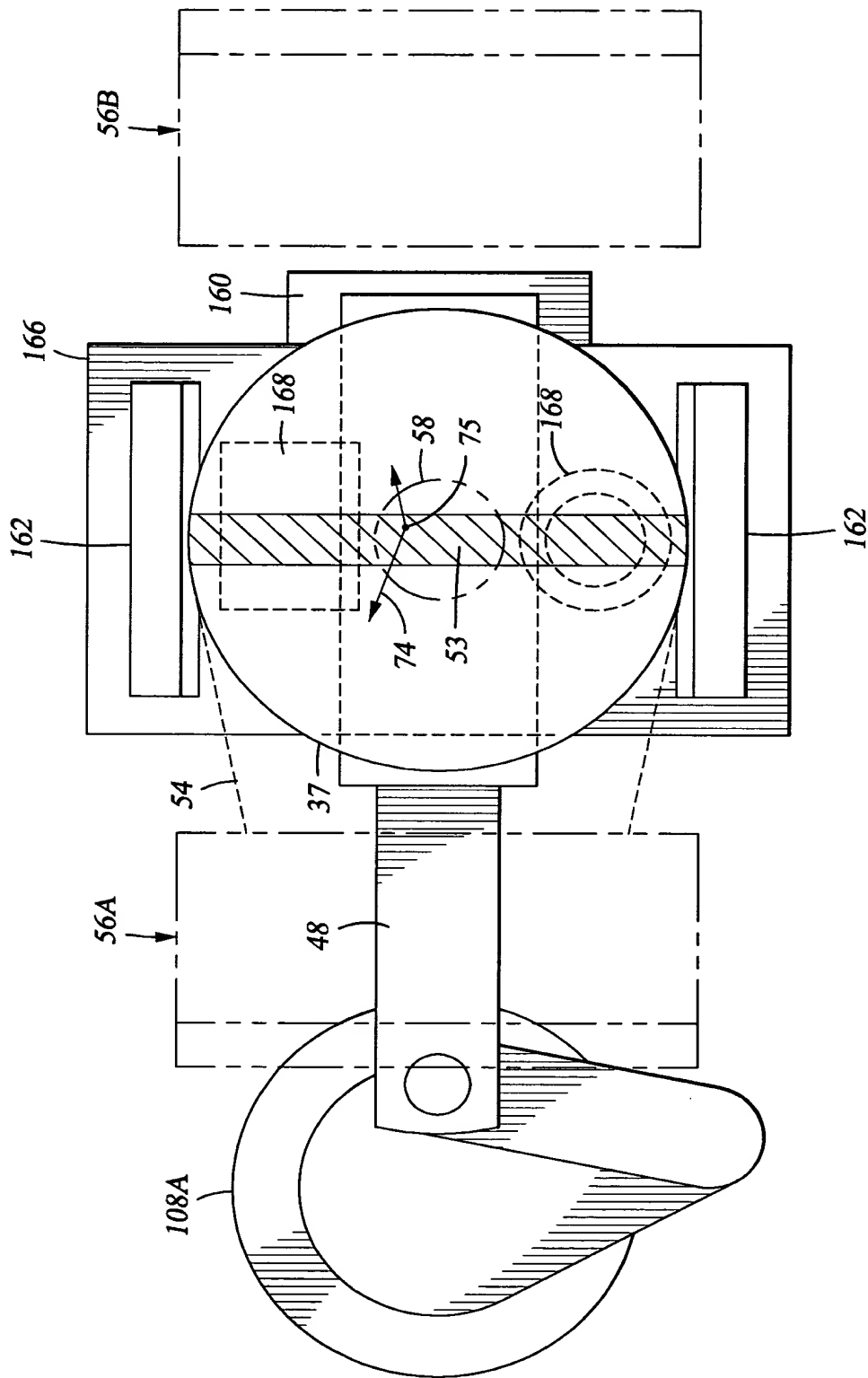


Fig. 3B

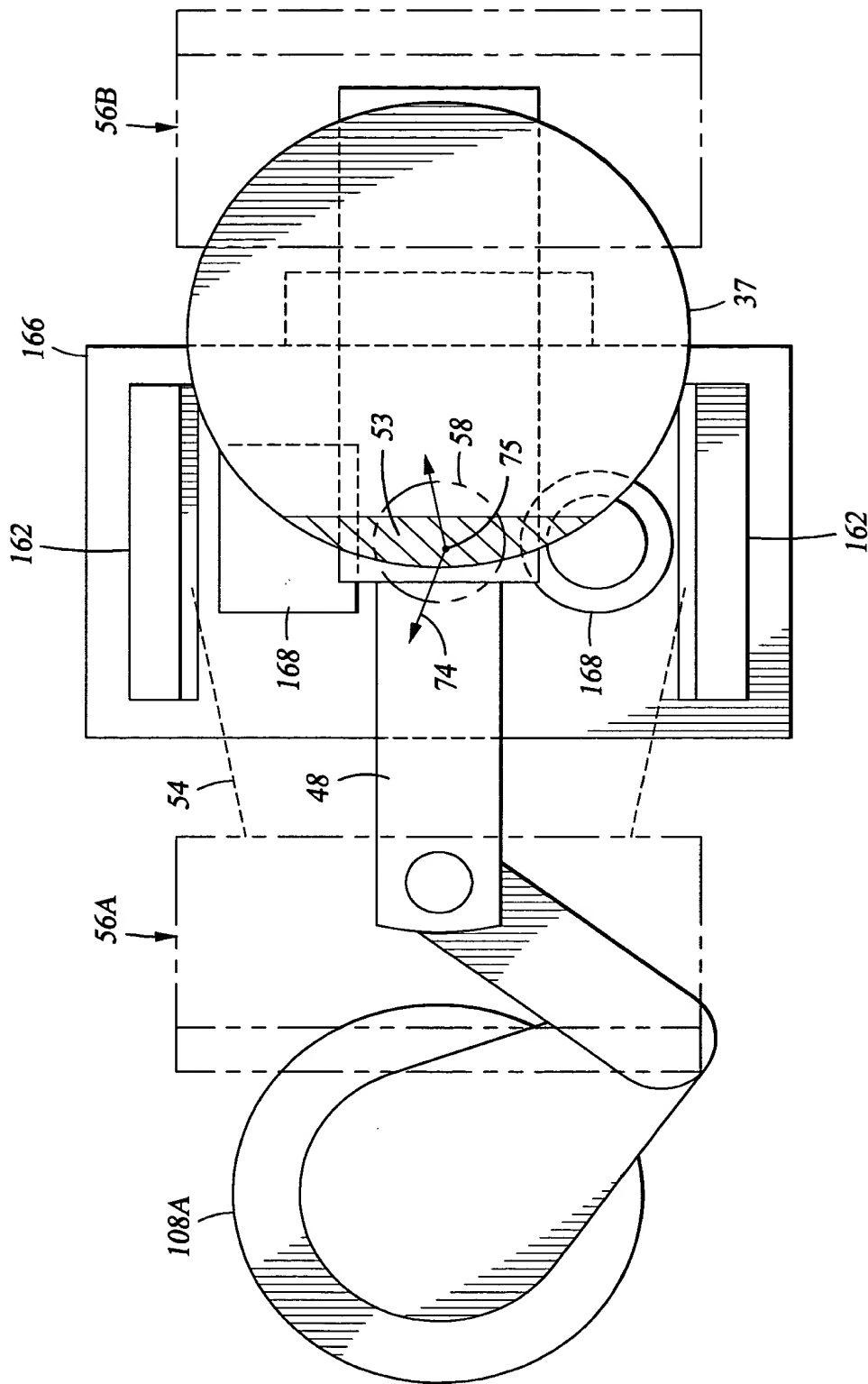


Fig. 3C

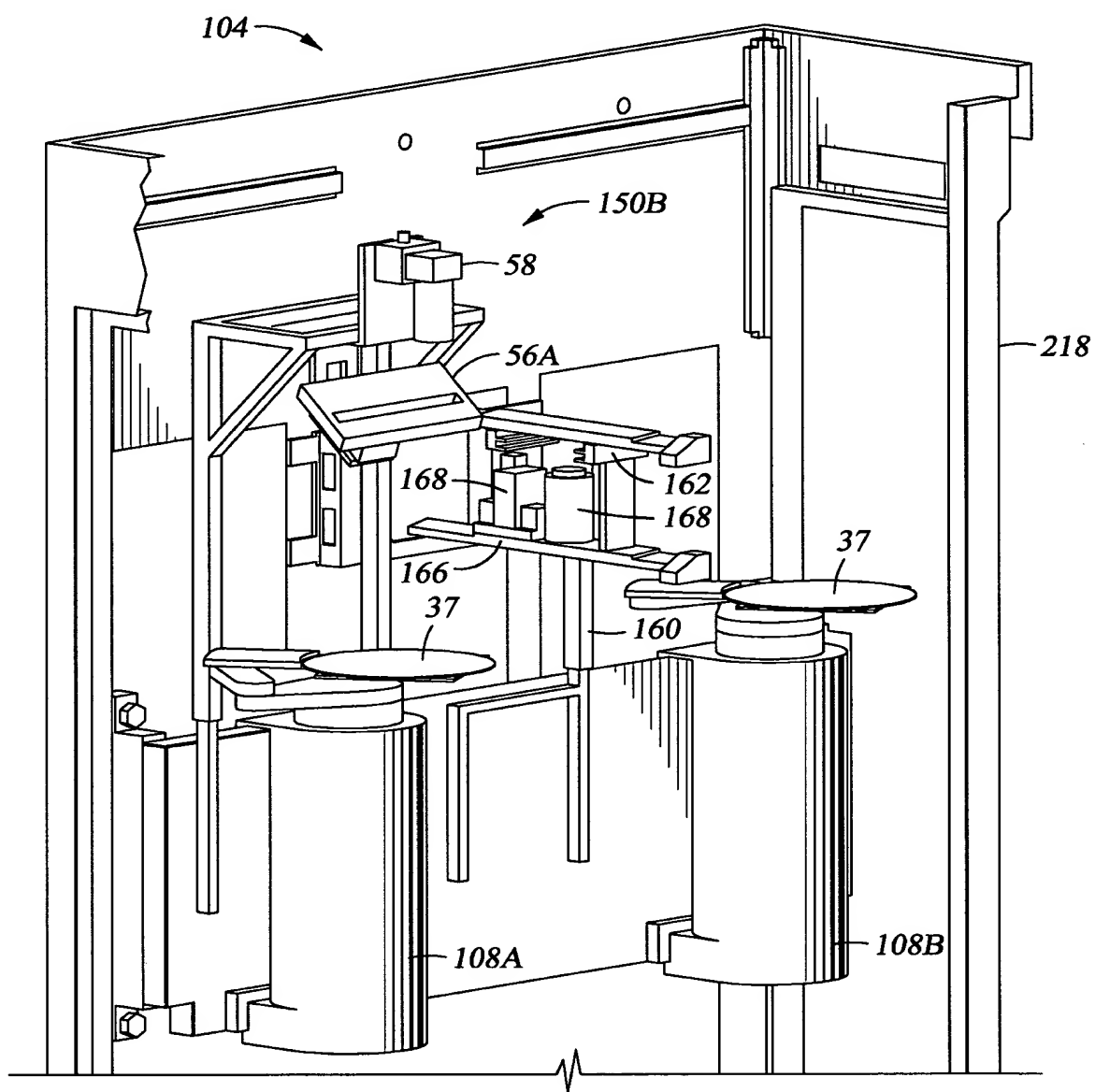


Fig. 4

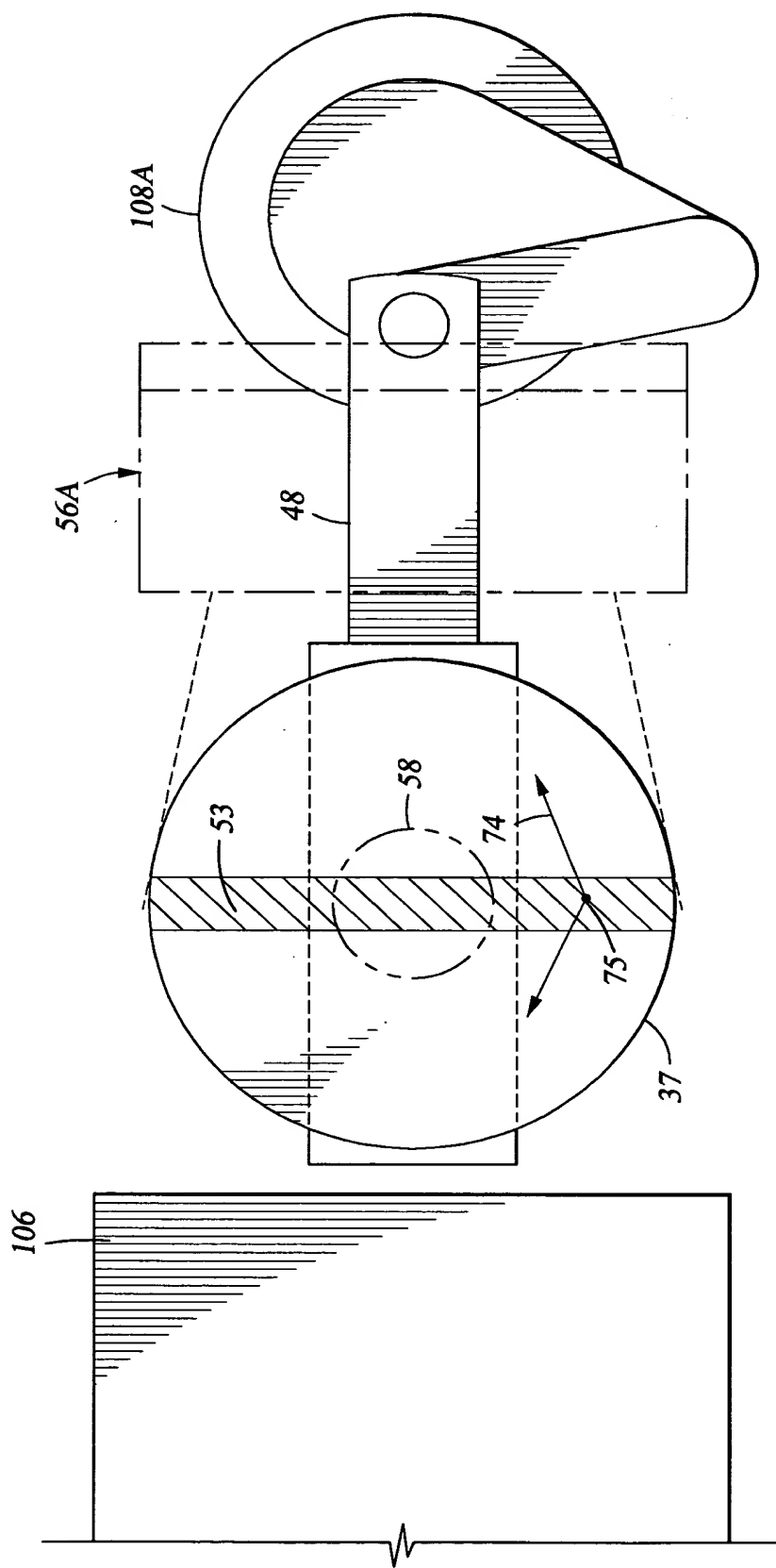


Fig. 5B

00900T 15T58960

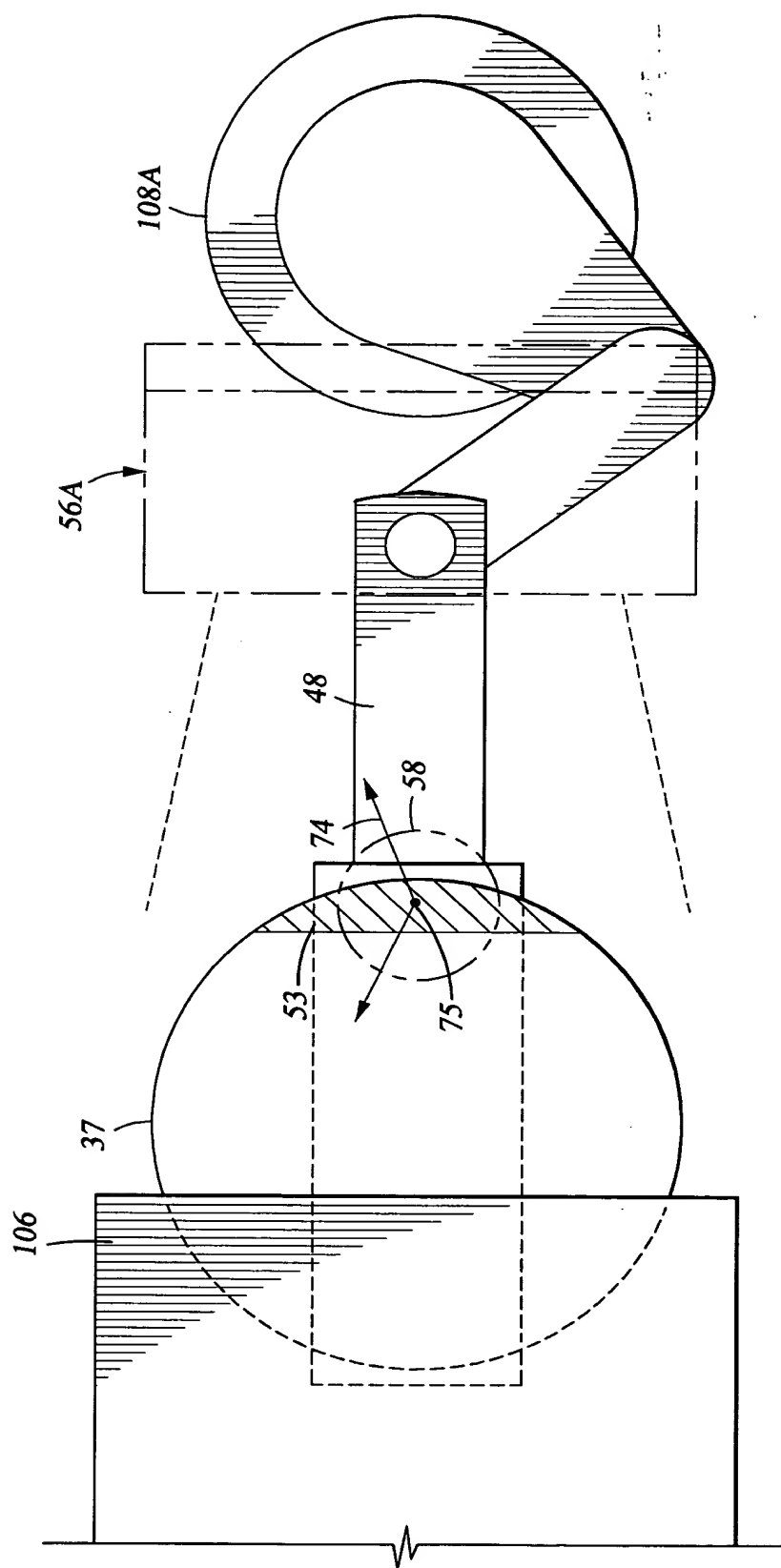
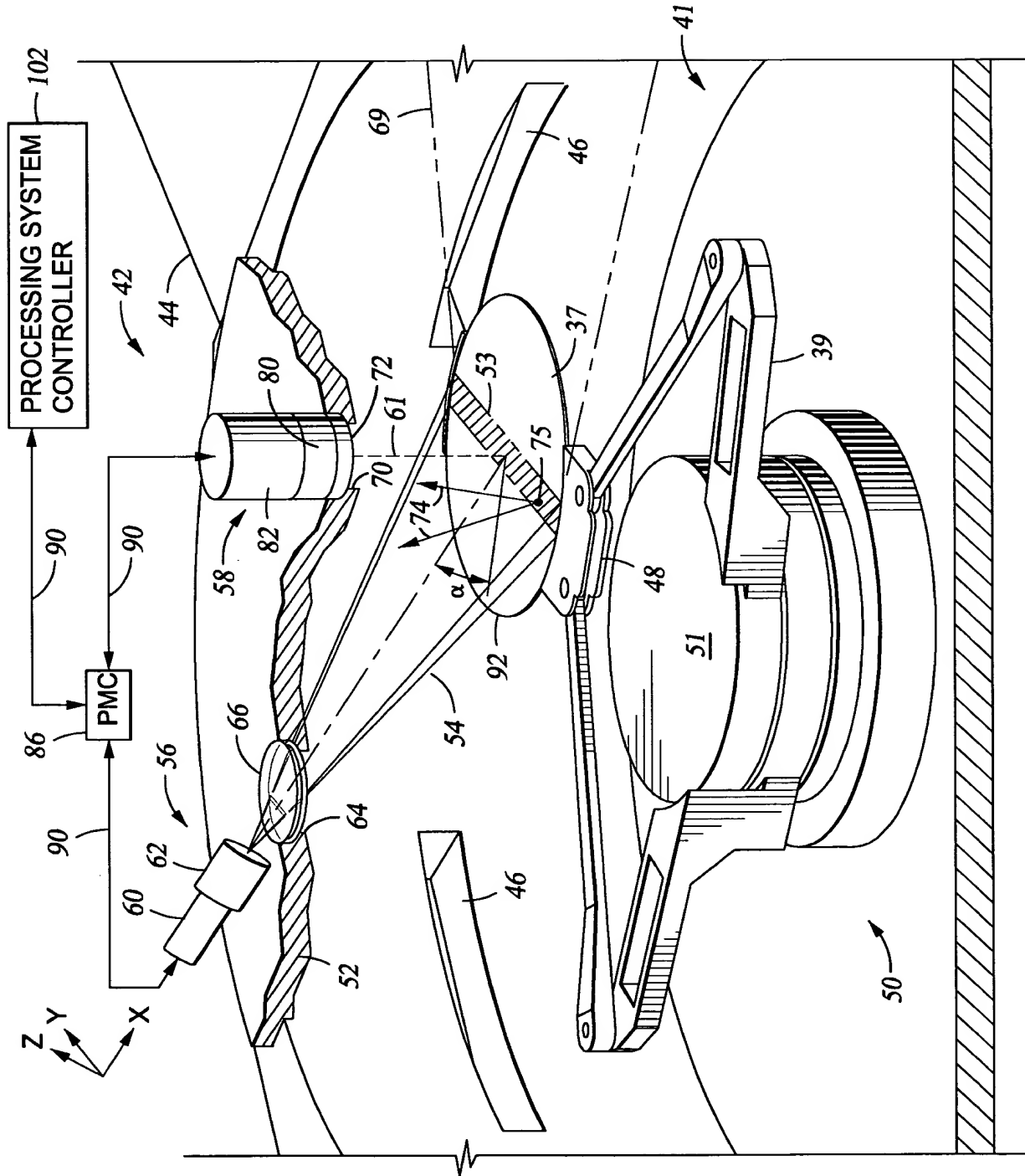


Fig. 5C

00500T 16T98960

Fig. 6



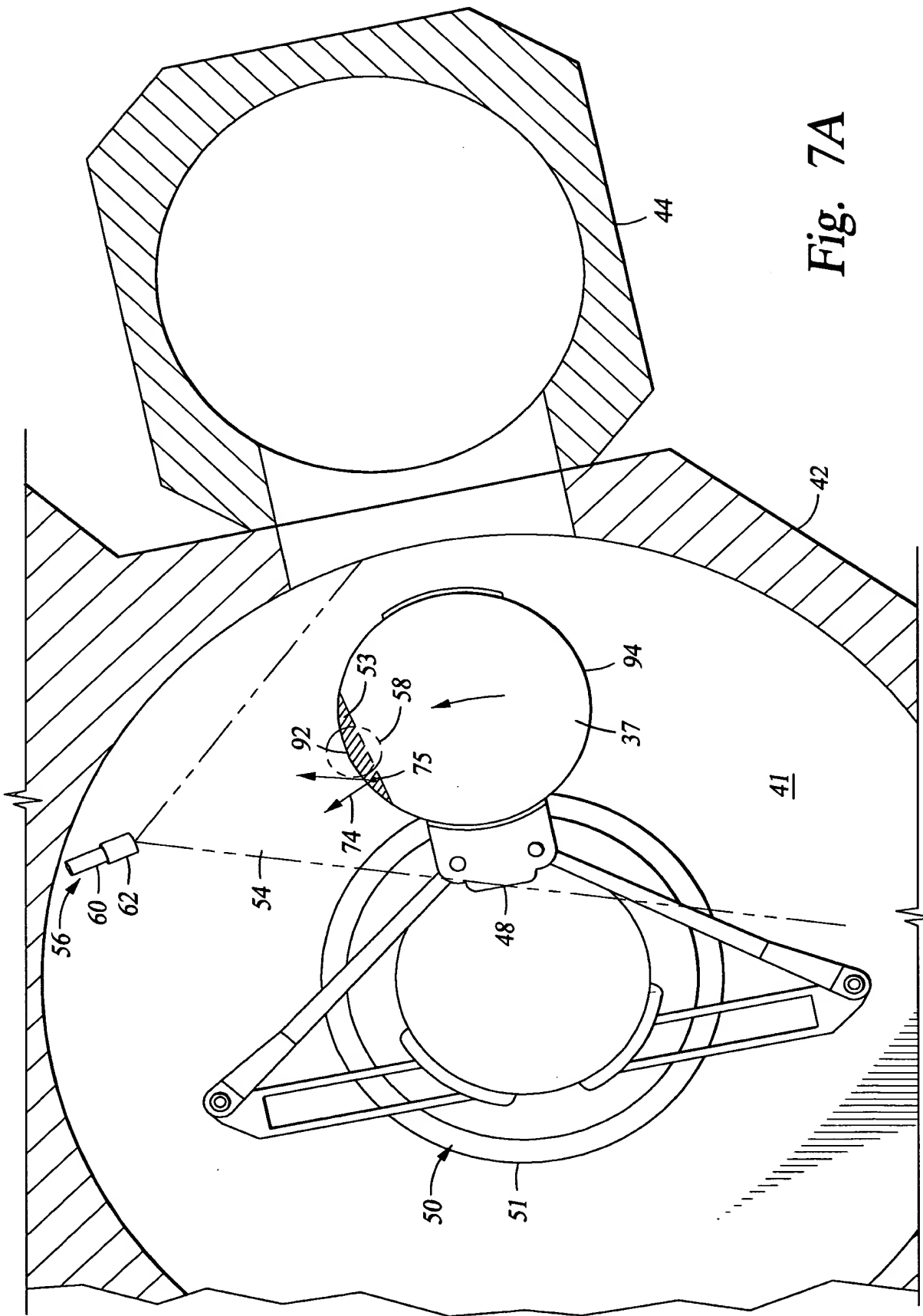
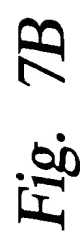


Fig. 7A



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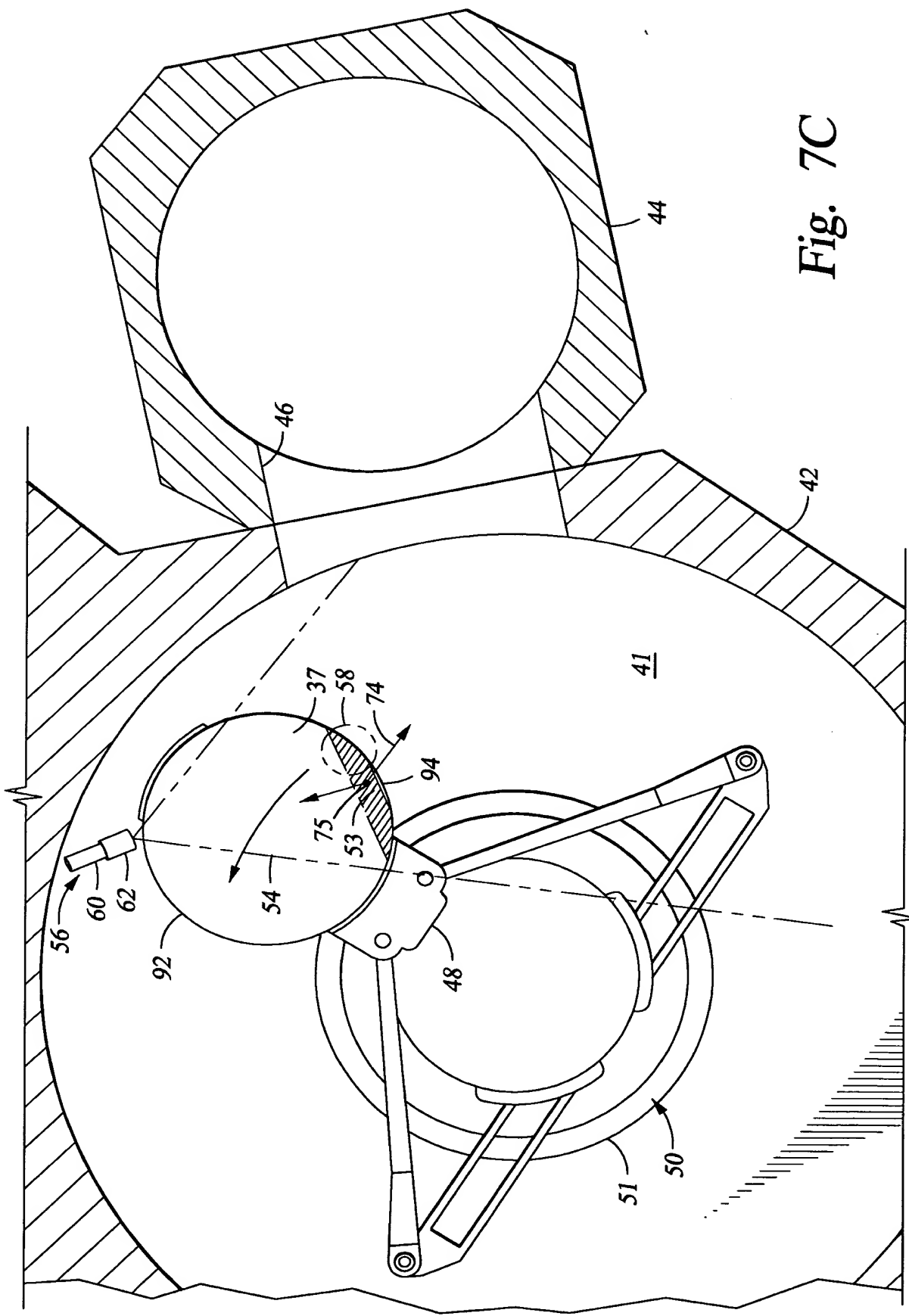
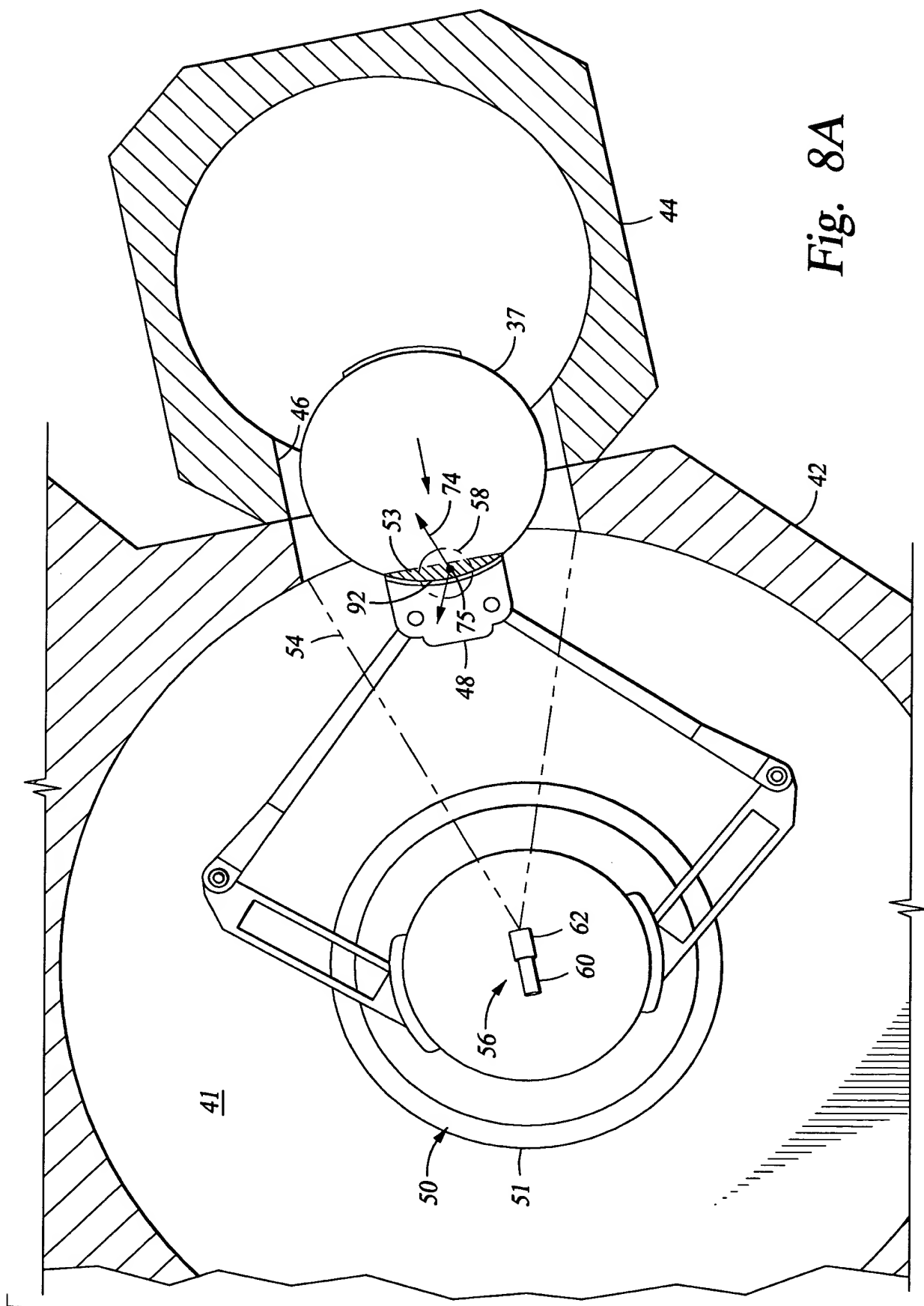
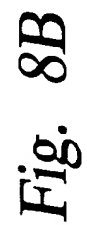


Fig. 7C

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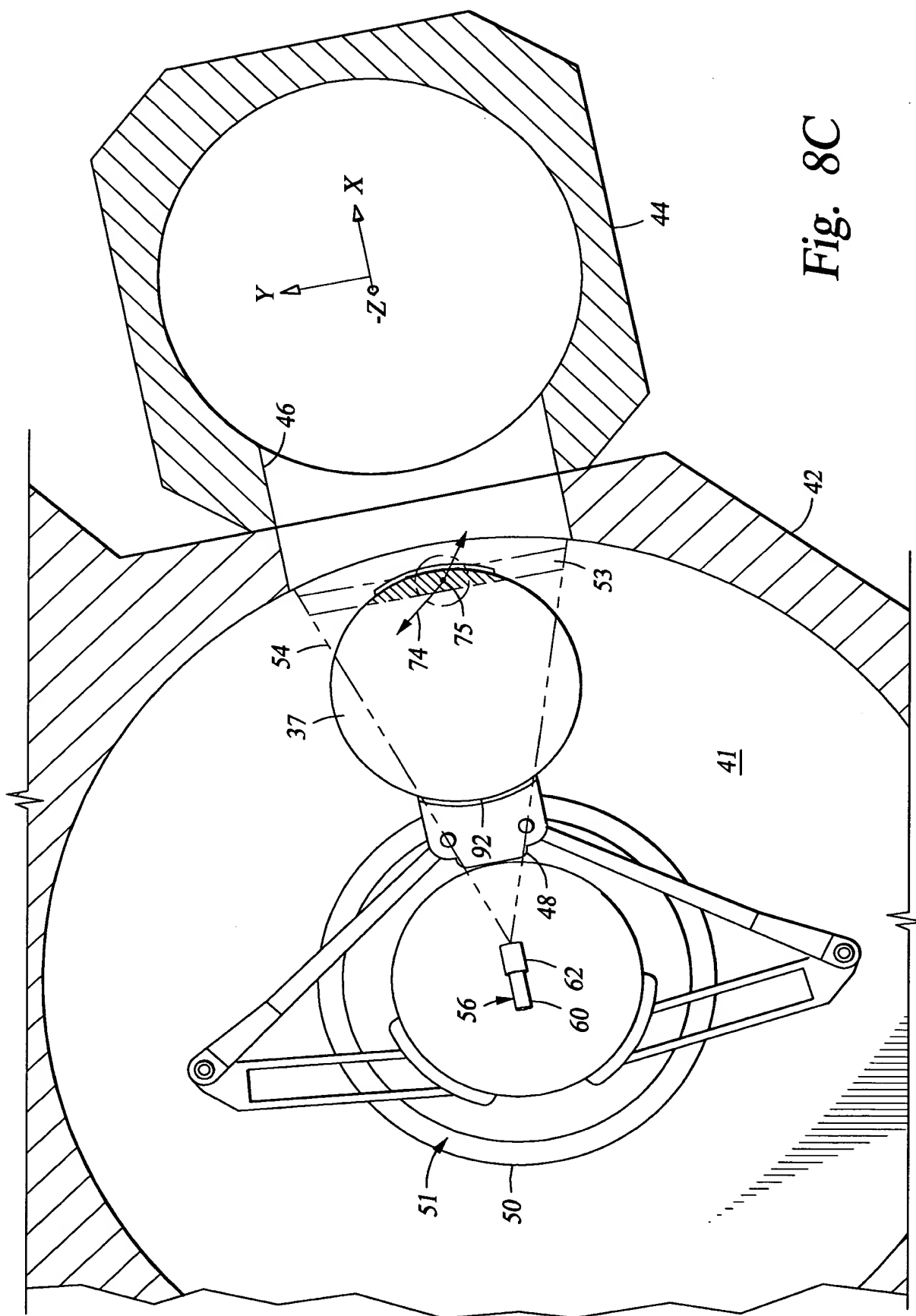


Fig. 9

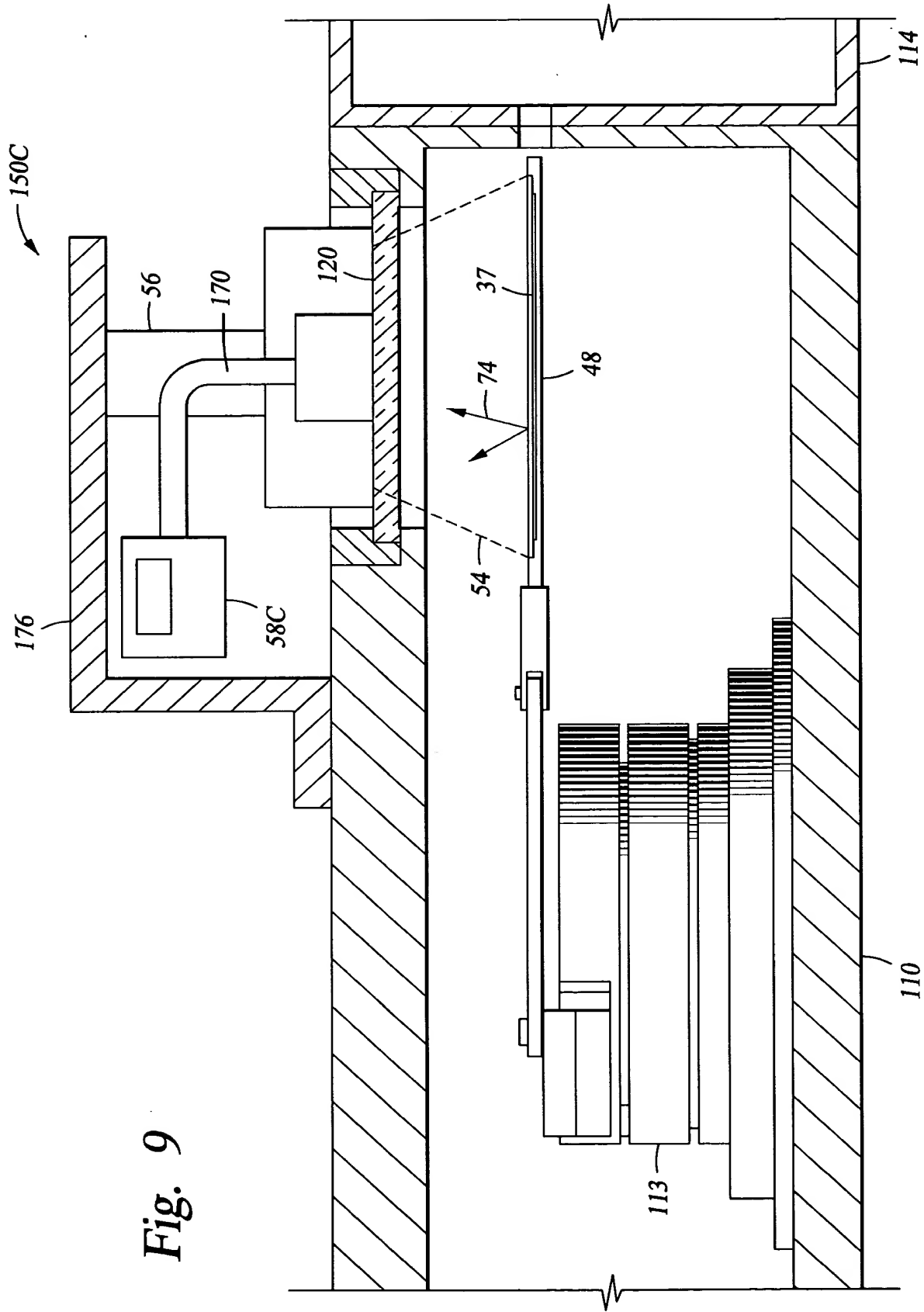
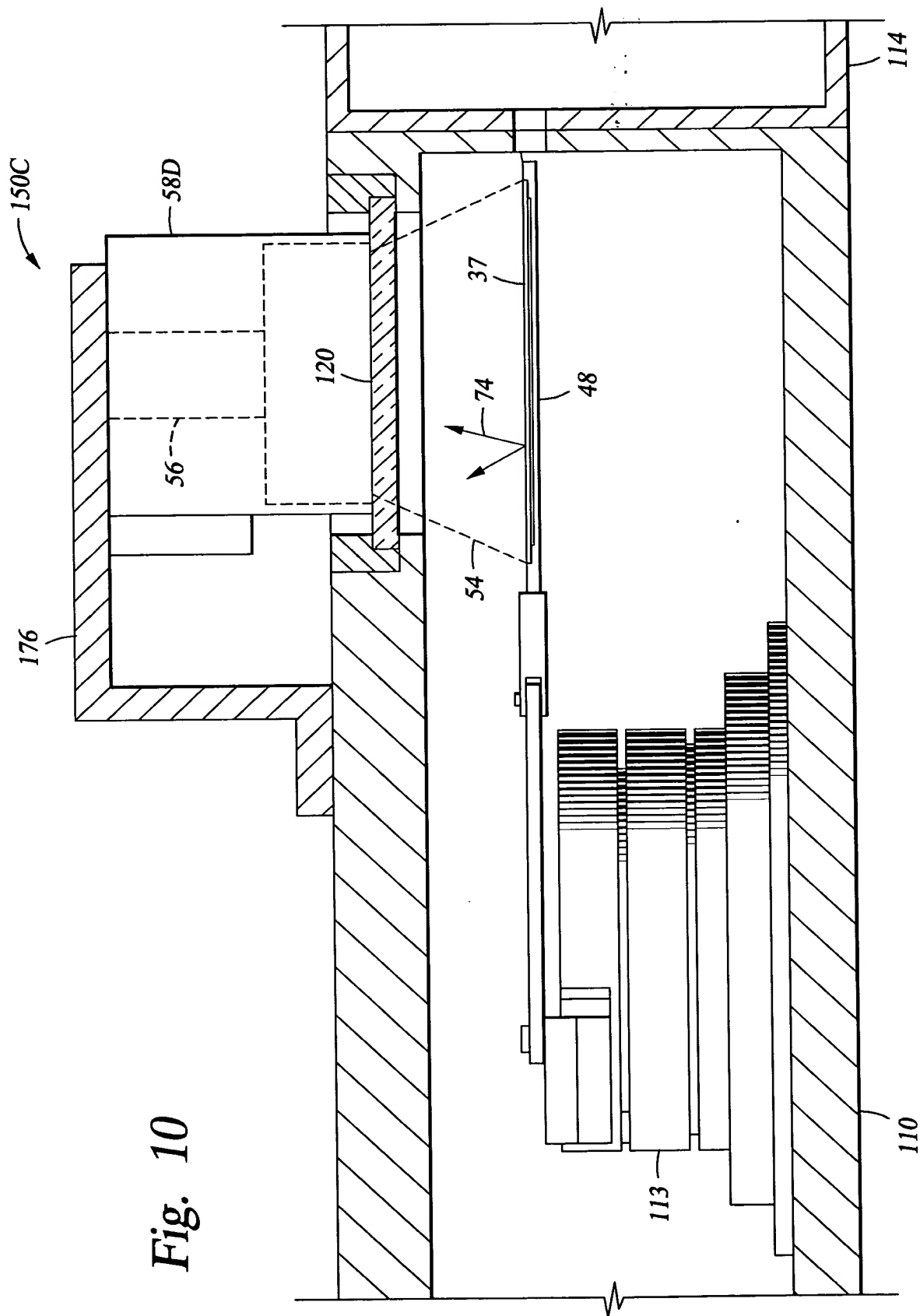


Fig. 10



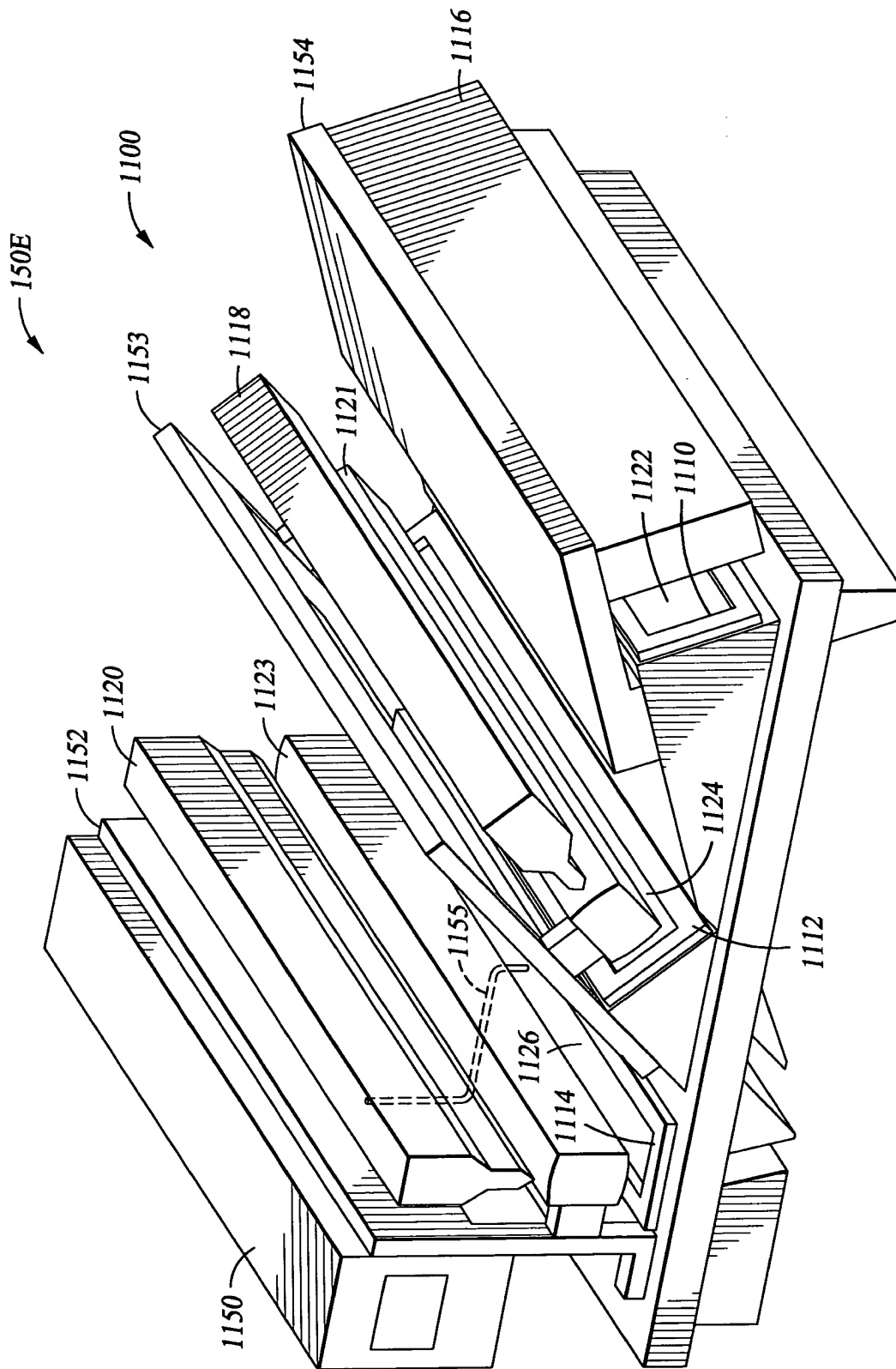


Fig. 11

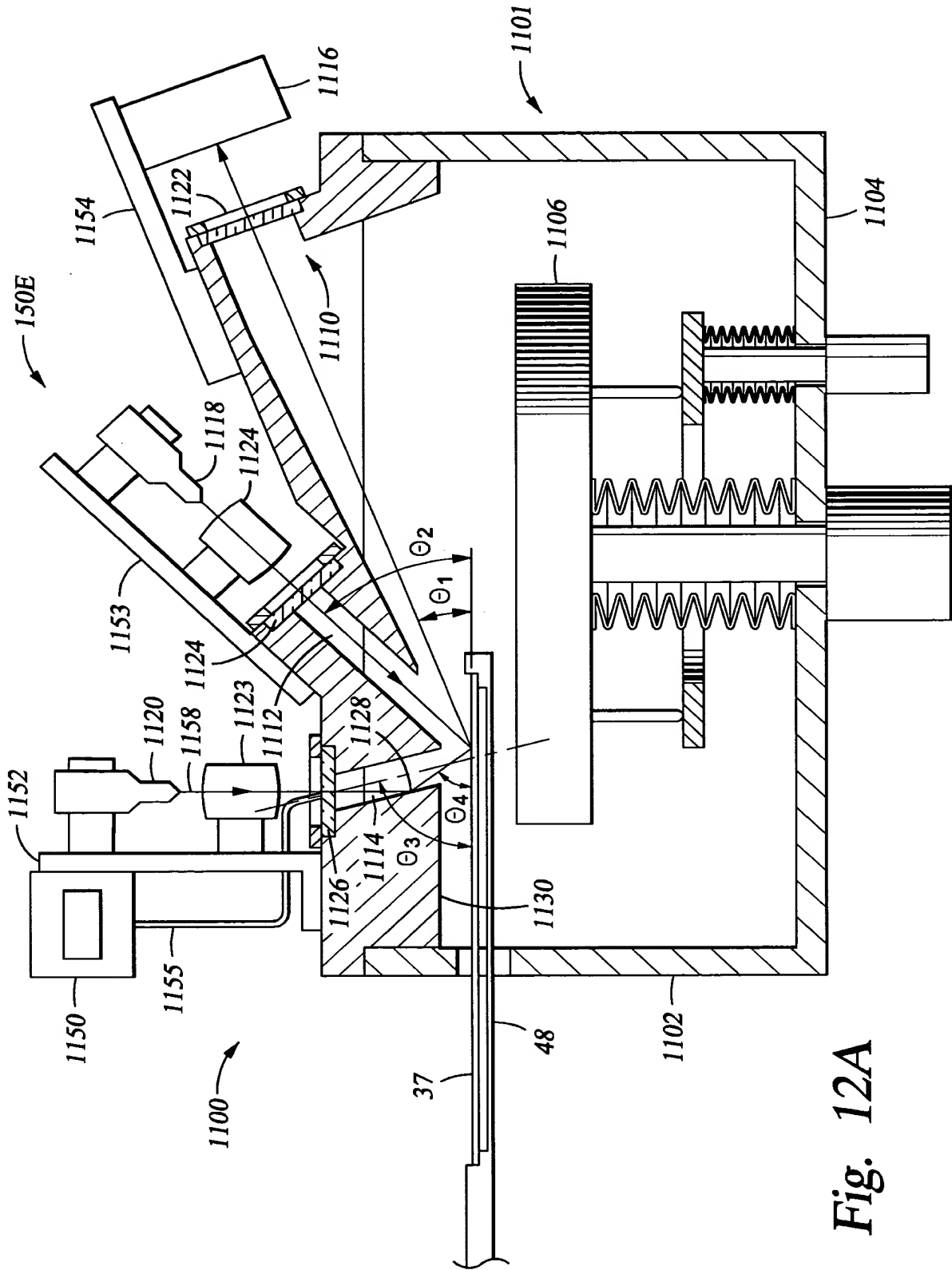


Fig. 12A

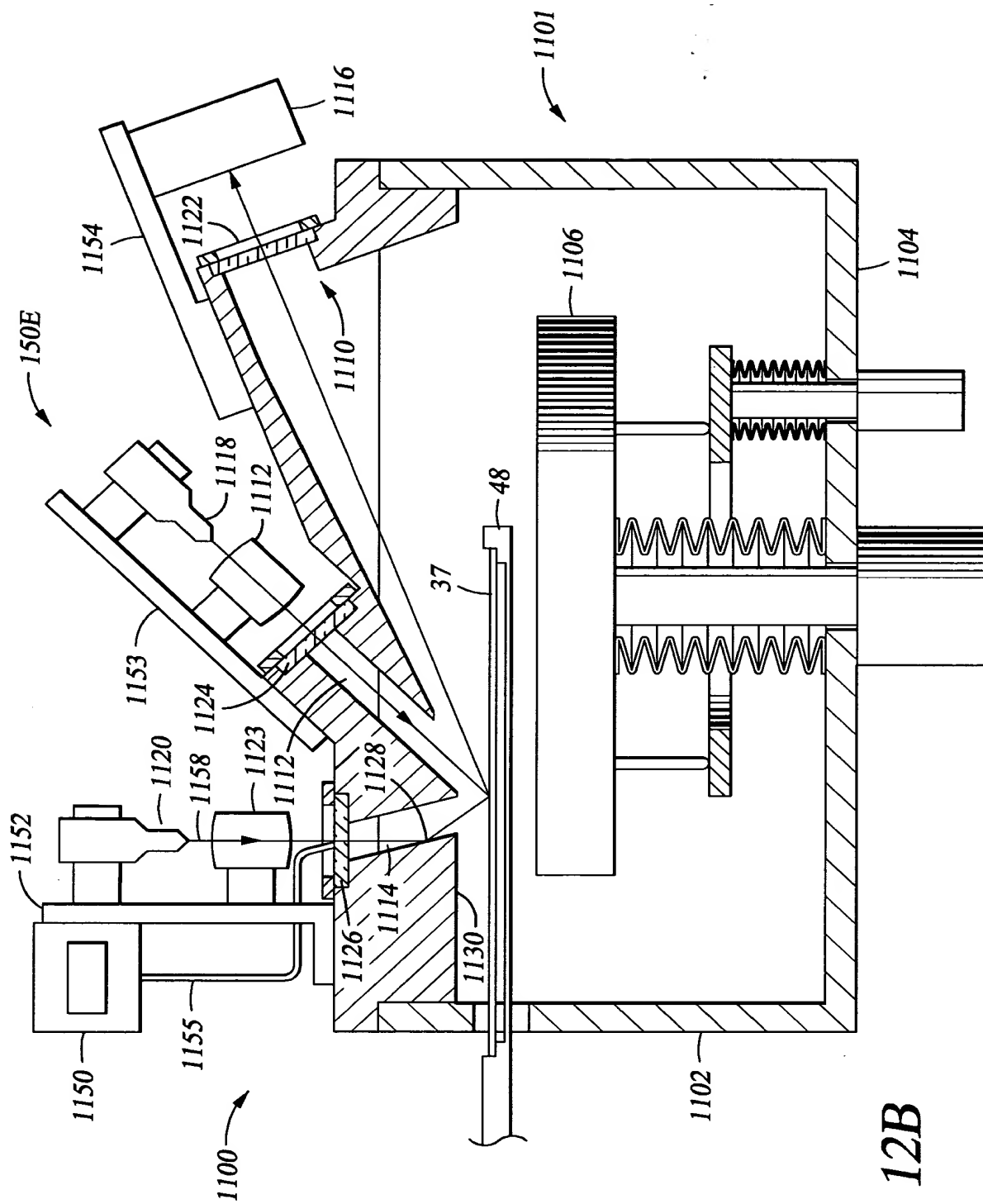


Fig. 12B

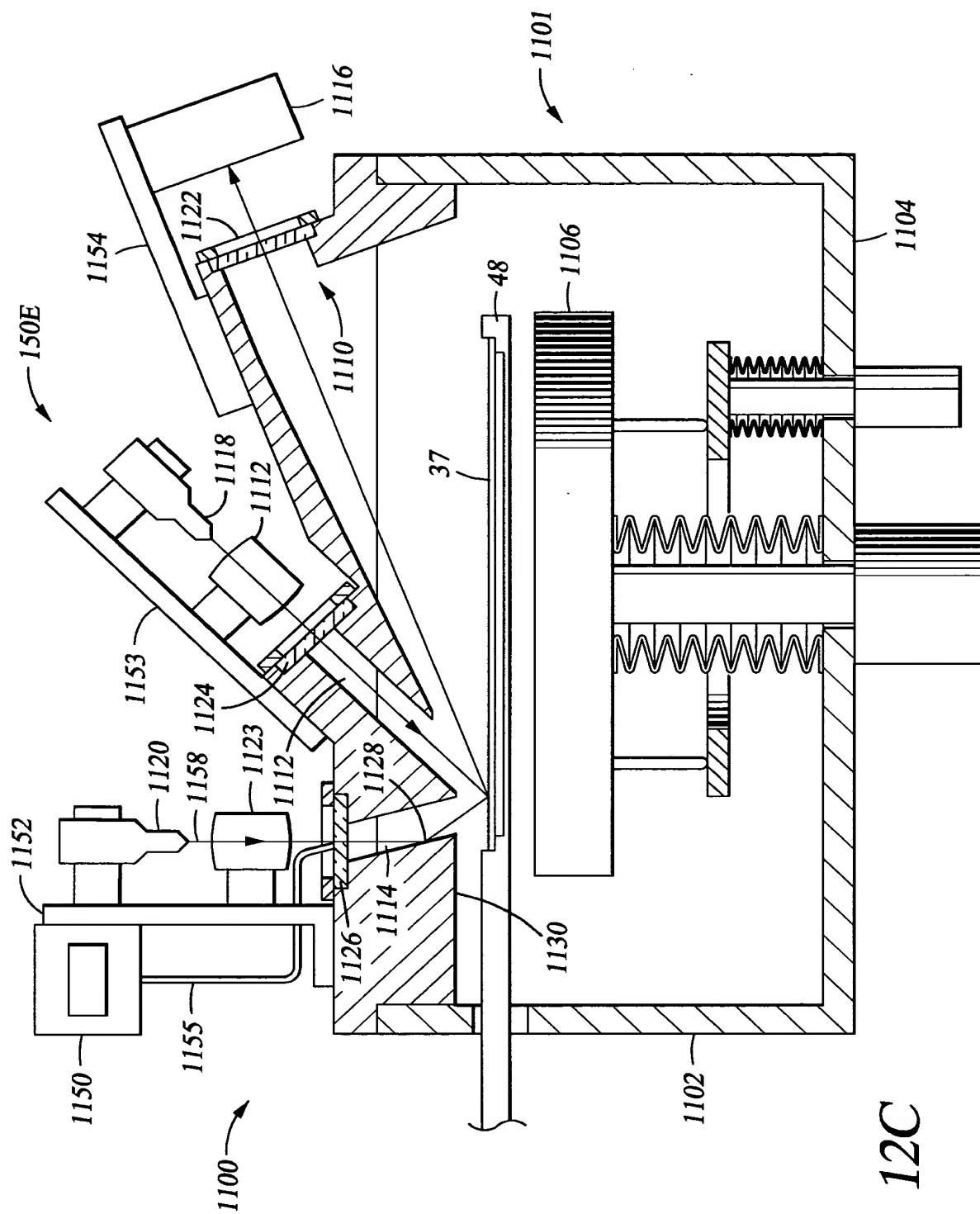
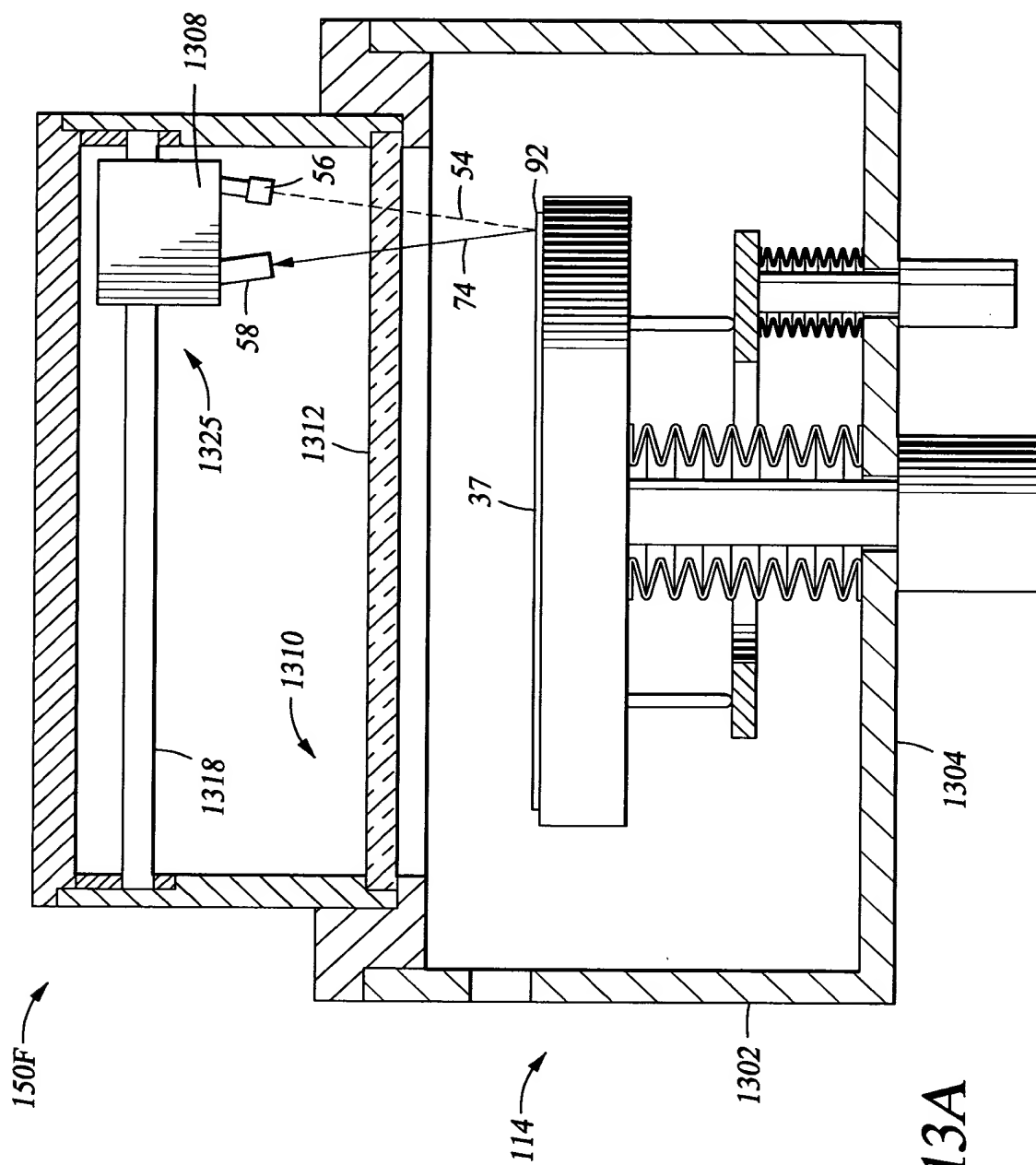


Fig. 12C



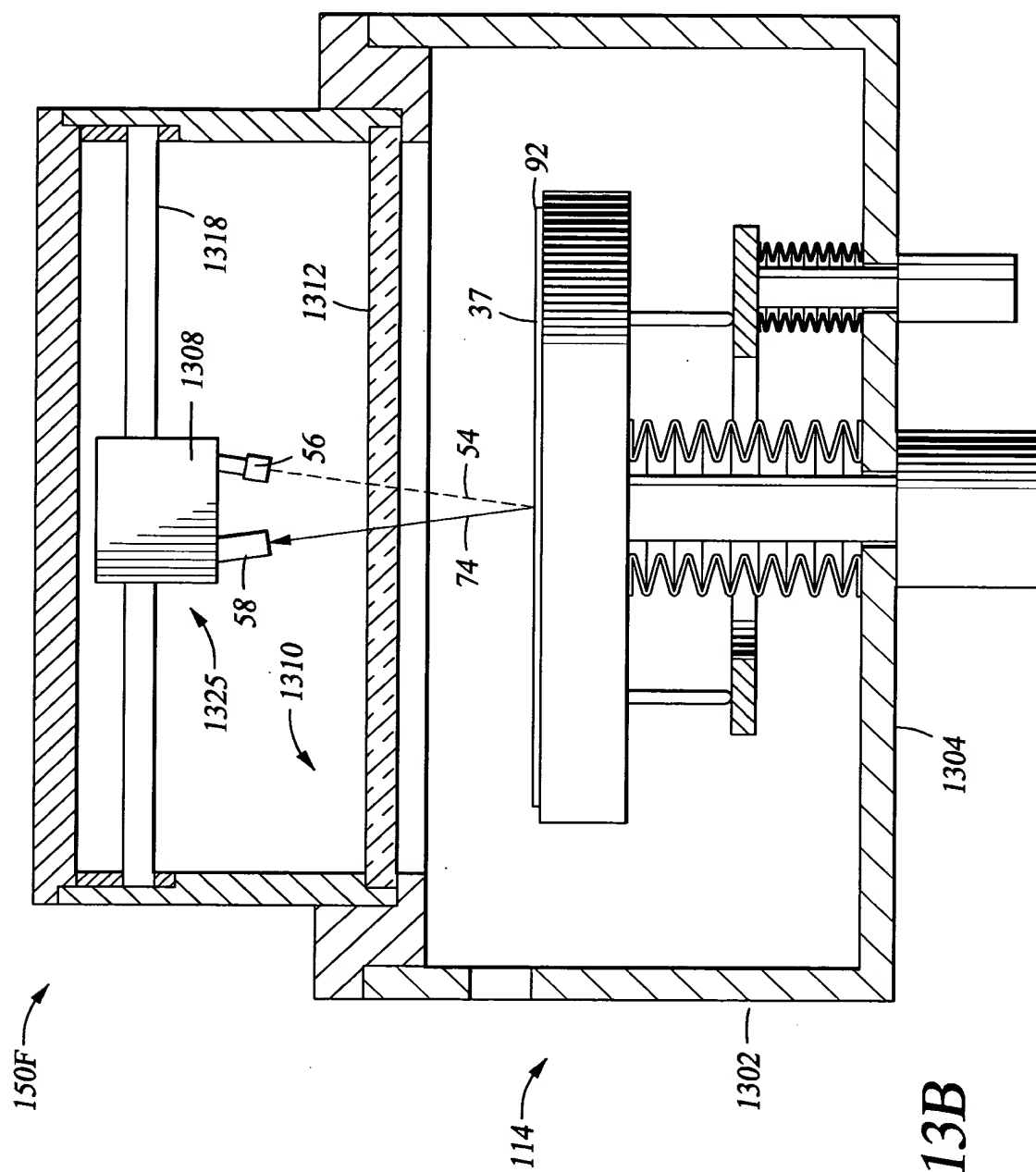




Fig. 13C

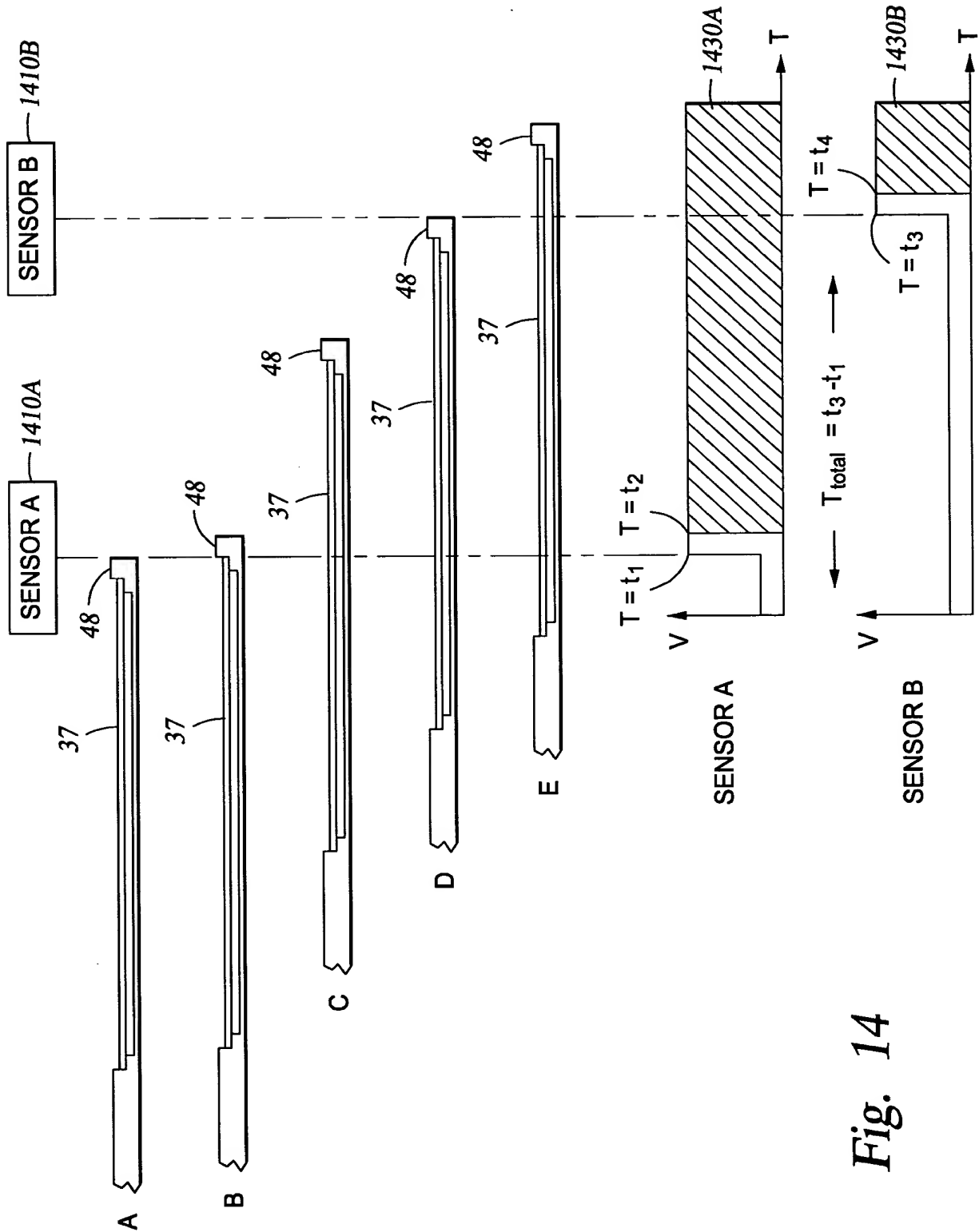
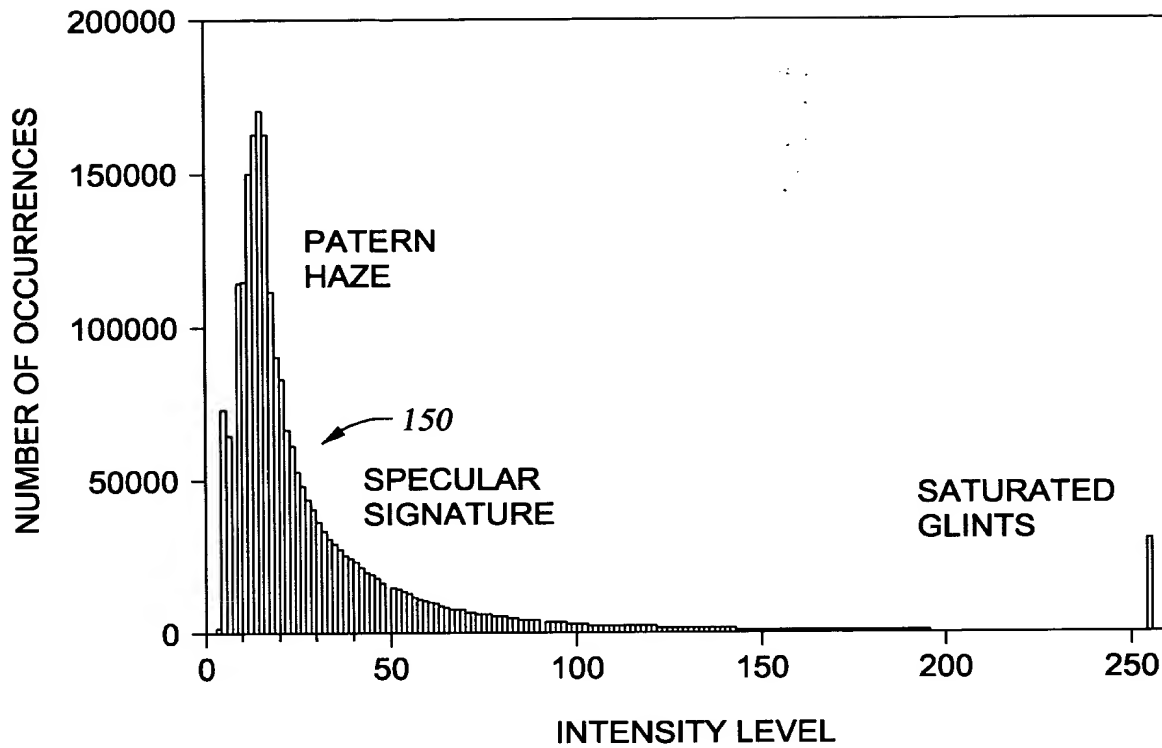
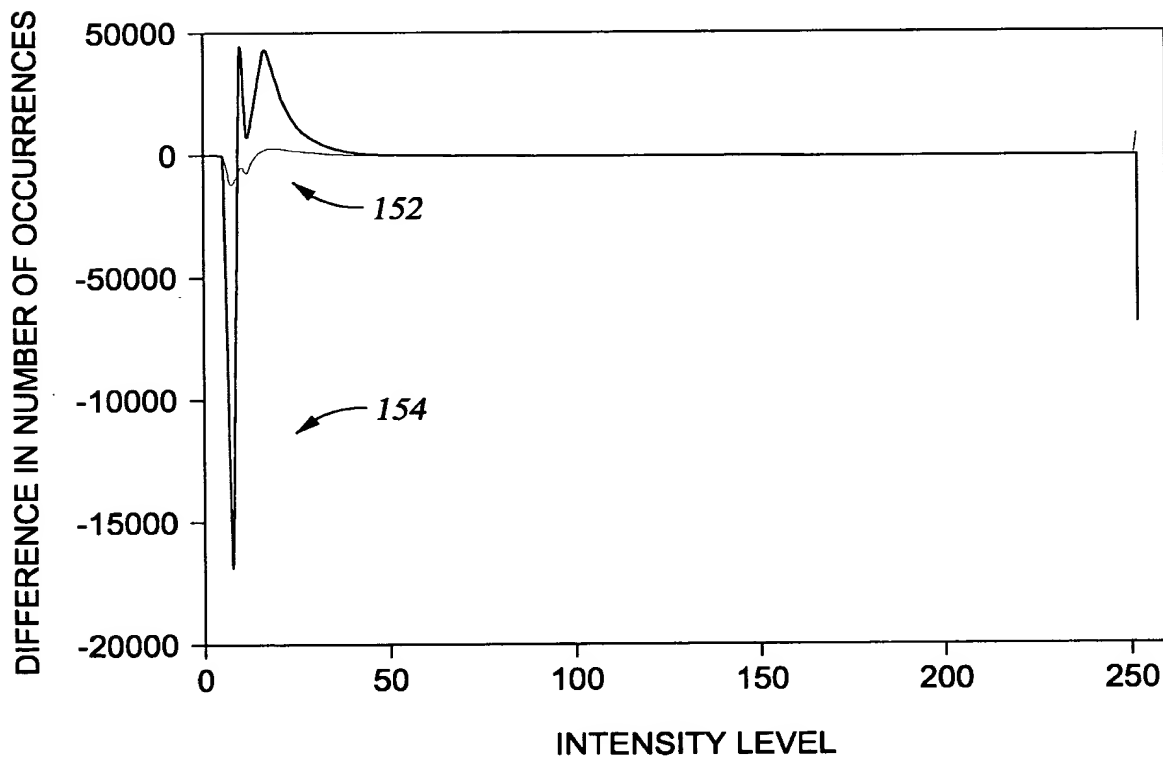


Fig. 14

*Fig. 15**Fig. 16*

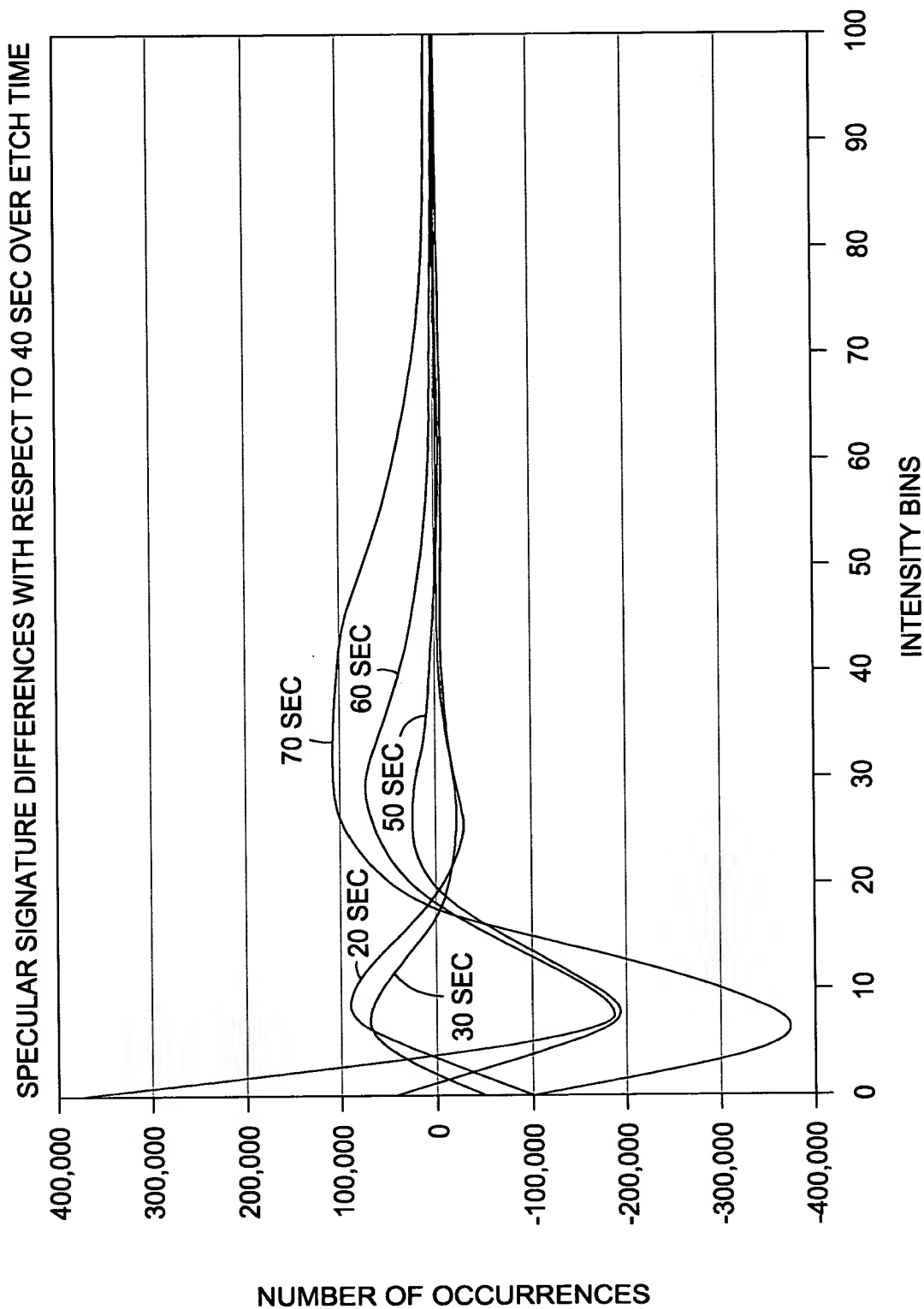


Fig. 17

TRADITIONAL ETCH ENDPOINT PLOT BASED ON CHANGES OF PROCES PLASMA

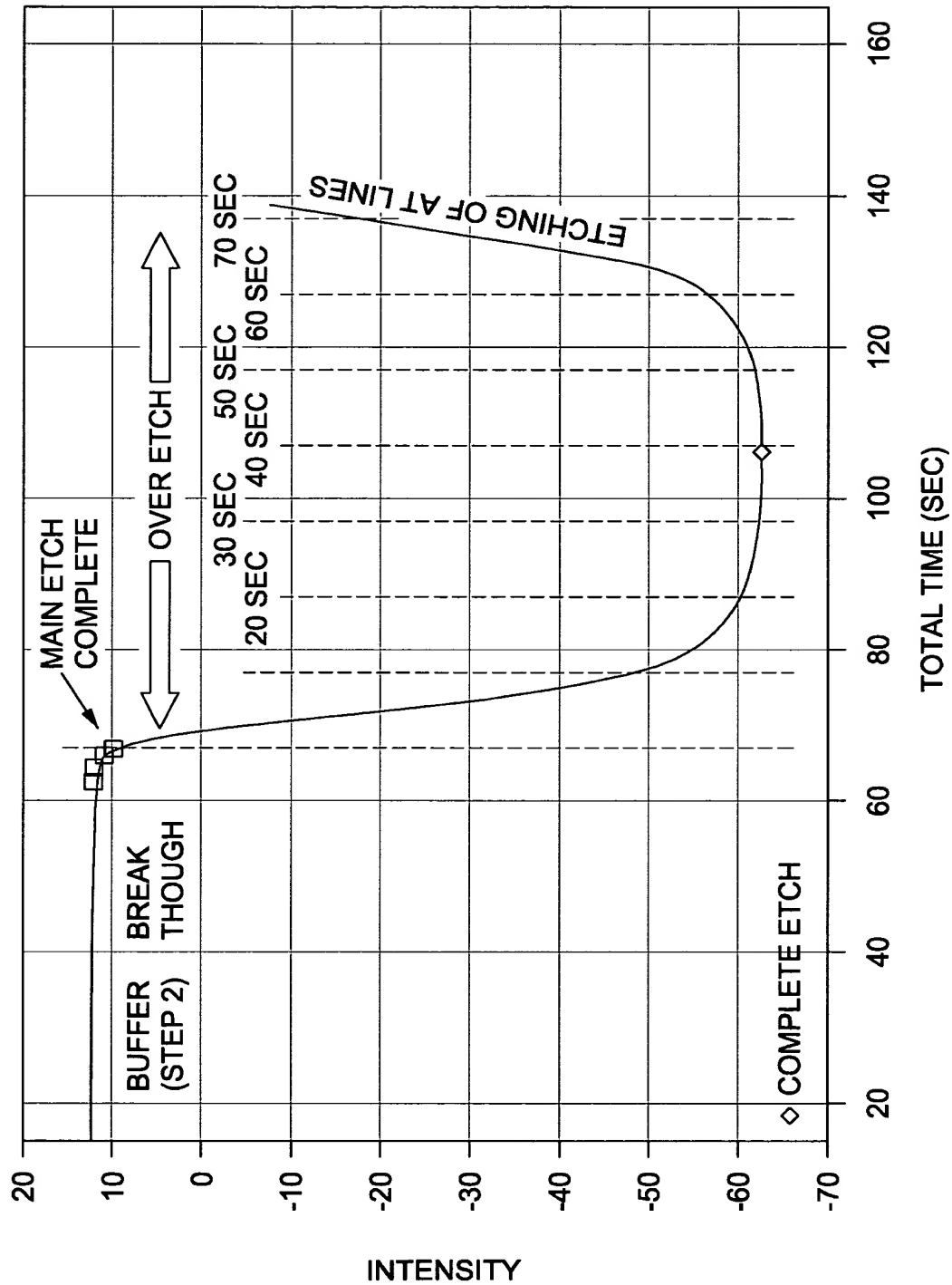


Fig. 18

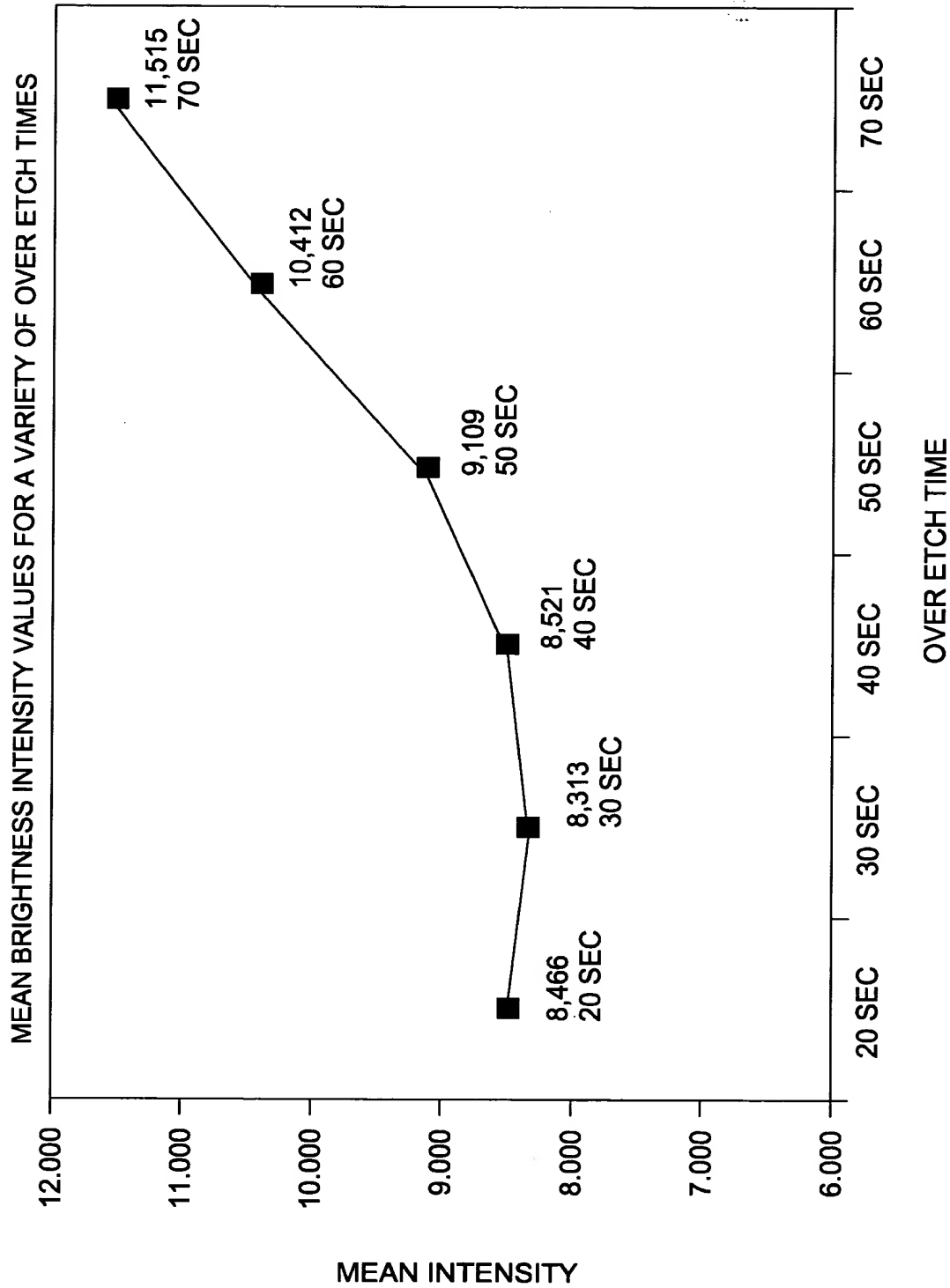


Fig. 19

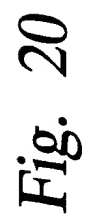


Fig. 20

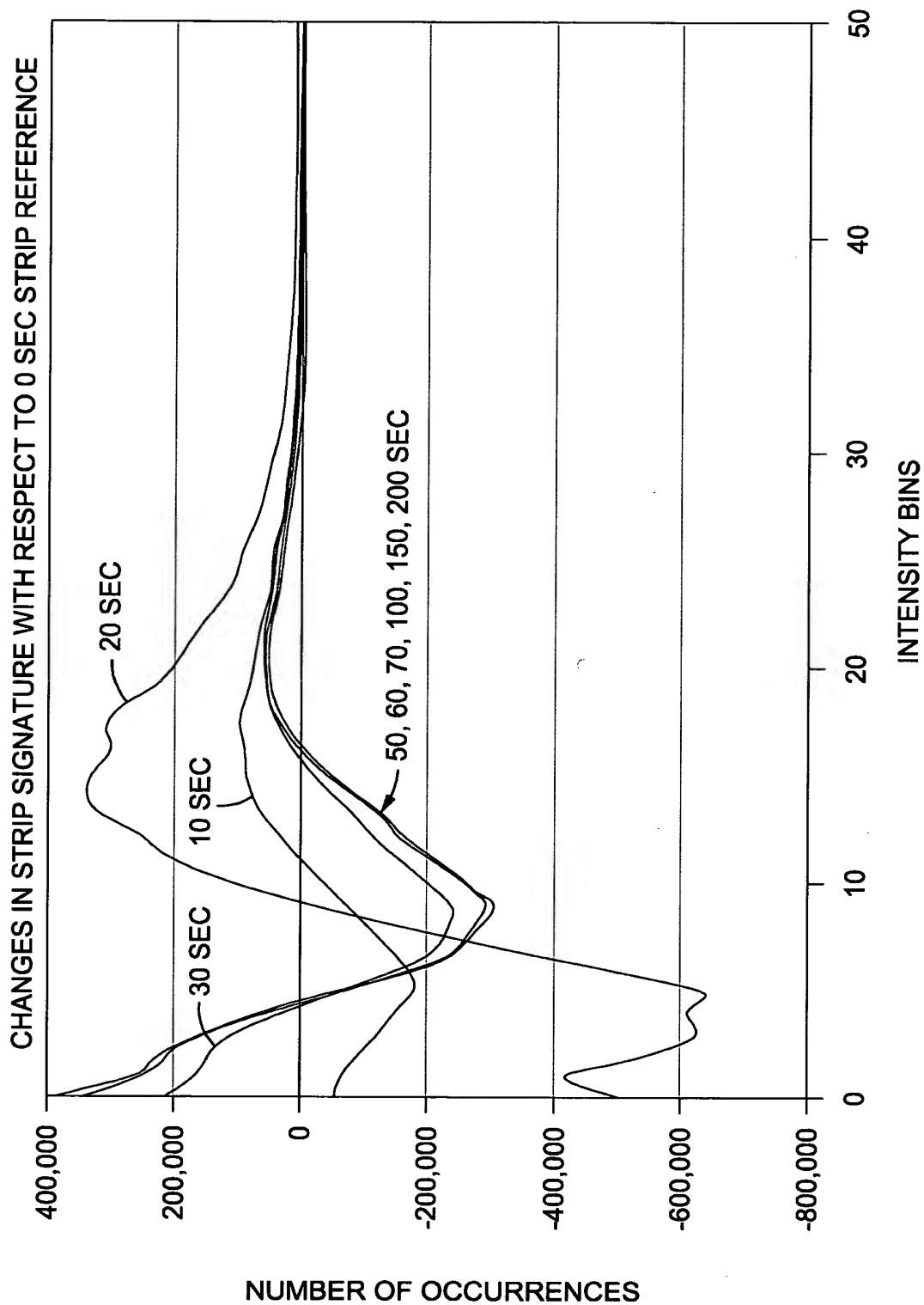


Fig. 21

DIFFERENCES IN STRIP SIGNATURES FOR STRIP TIMES LESS THAN 50 SECONDS WITH RESPECT TO AN OPTIMUM REFERENCE STRIP SIGNATURE

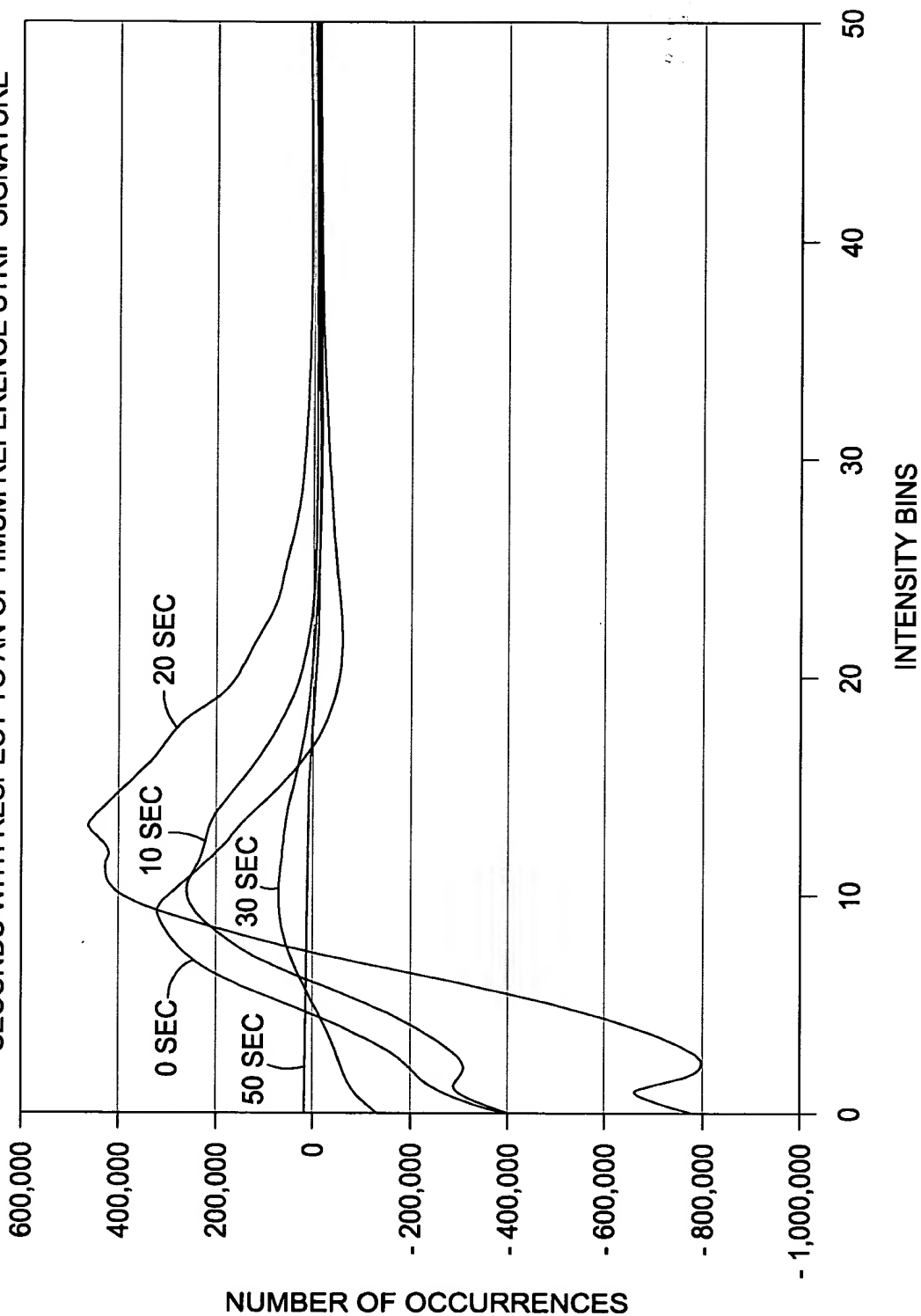


Fig. 22

DIFFERENCES IN STRIP SIGNATURES FOR STRIP TIMES EXCEEDING 50 SECONDS WITH RESPECT TO AN OPTIMUM REFERENCE STRIP SIGNATURE

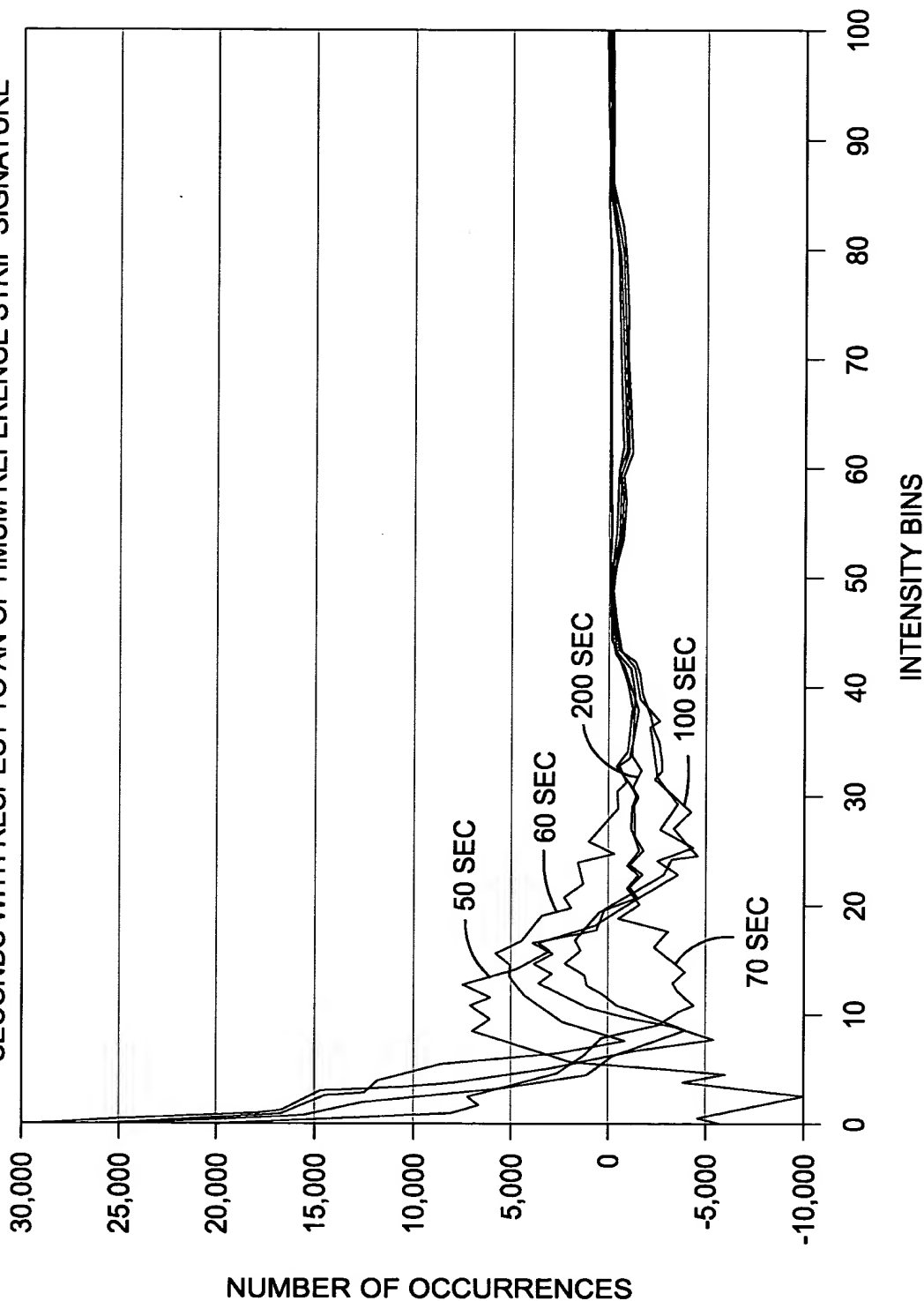


Fig. 23

SYSTEM GENERATED SCAN TO SCAN VARIANCES OF AN OPTIMALLY STRIPPED SUBSTRATE

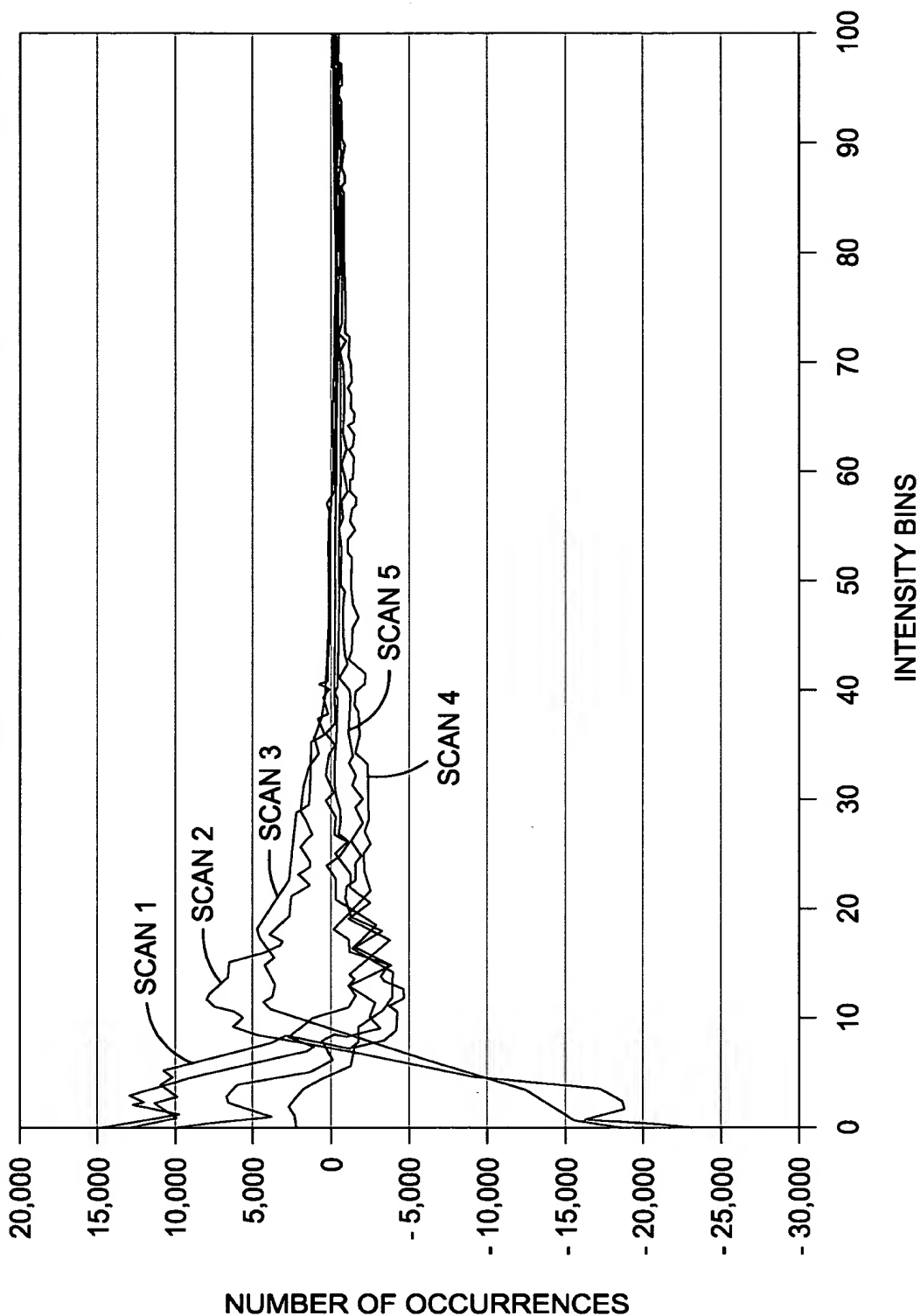


Fig. 24



Fig. 25

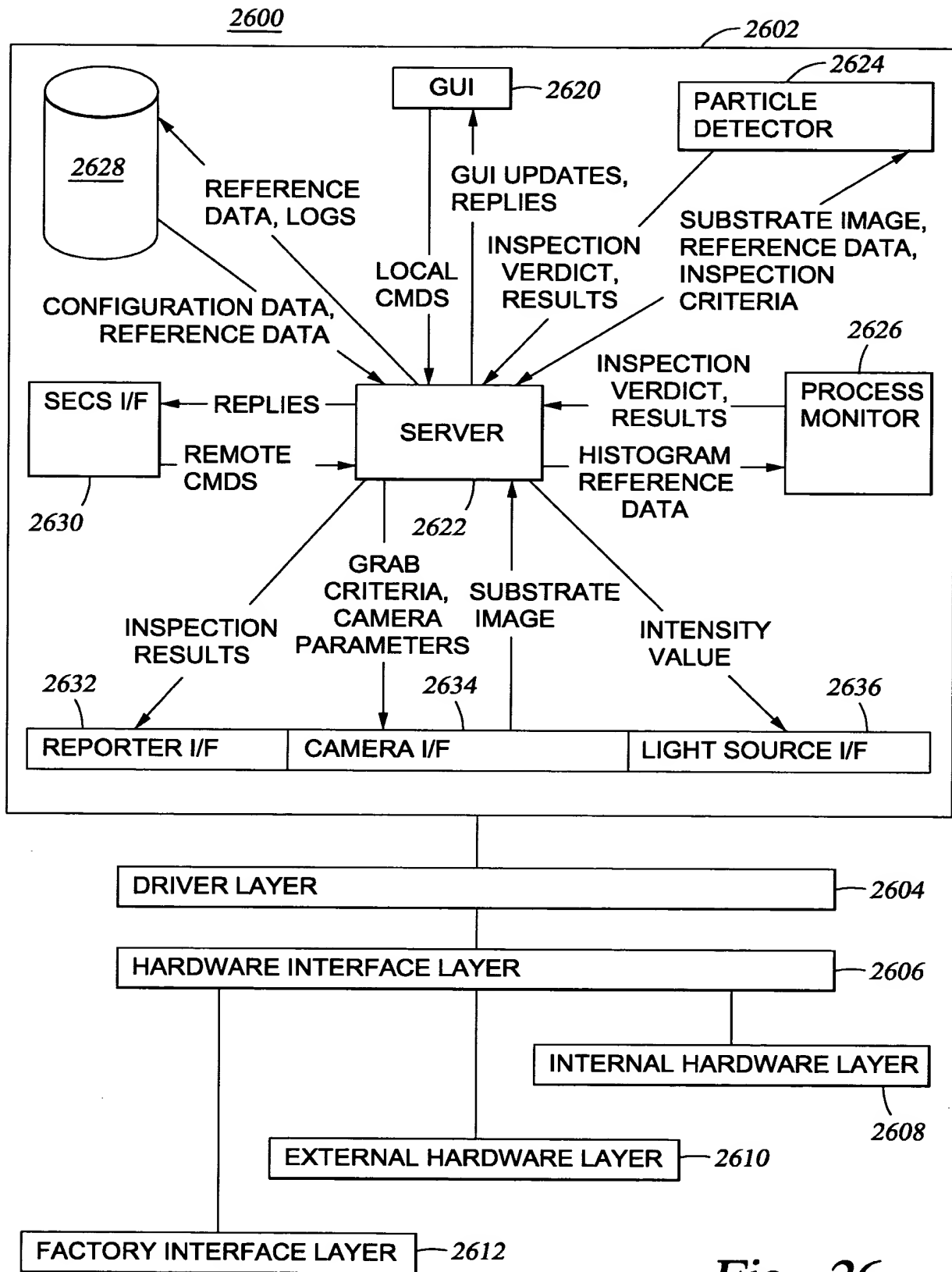


Fig. 26

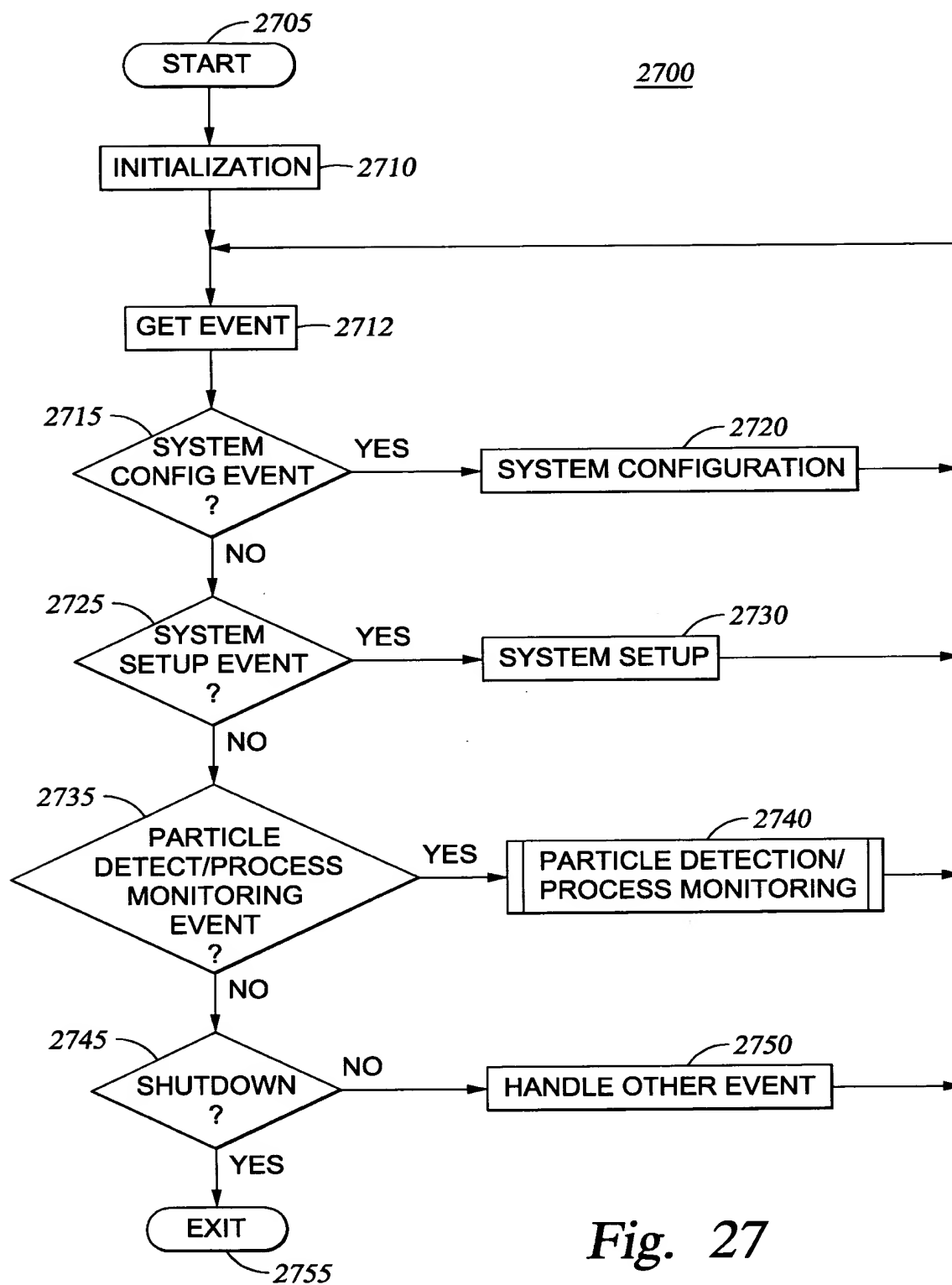


Fig. 27

Fig. 28

